

## **General Description**

The epc635 is a fully integrated 3D-TOF imager with a resolution of 160 x 60 pixels (Half-QQVGA). As a system on chip, the epc635 contains next to the CCD pixel-field the complete control logic to operate the device. The output of the chip is 12 bit DCS distance data per pixel, which are accessible through a high-speed digital 8-bit parallel video interface.

Only few additional components are needed to generate a complete 3D camera. Depending on illumination power and optical design, a resolution in the millimeter range for distances up to dozens of meters is feasible. Up to 512 full frame TOF images are delivered in rolling mode. The extremely high sensitivity of the chip allows for a reduced illumination power and reduced overall power consumption compared to other TOF imagers.

epc635 is based on the same technology and instruction set as the epc660 QVGA TOF imager from ESPROS.

An evaluation kit for the epc635 is available with hard- and software examples and a comprehensive manual to speed up system integration.

# **Applications**

- People detection and counting
- Postal parcel size measurement
- Machine safety
- Helicopter near terrain flight assistance
- ADAS systems
- Pedestrian detection and breaking systems
- Man-Machine interface
- Gesture control
- Body size measurement
- General volumetric mapping
- Mobile robotics
- Simultaneous localization and mapping (SLAM)

# **Block Diagram**

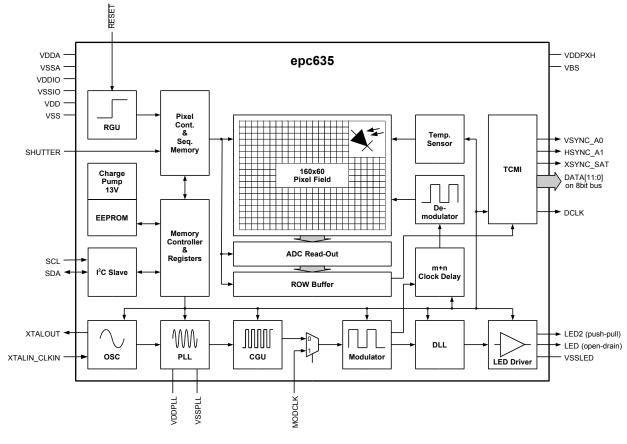


Figure 1: Functional block diagram

## **Main Features**

#### ■ General

- □ 3D TOF imager in full monolithic design
- □ 160 x 60 pixel-field, backside illuminated
- $\hfill \hfill \hfill$
- □ Integrated temperature sensor

### ■ Measurement performance

□ Absolute accuracy in the centimeter range with appropriate setup and calibration

### ■ Integrated LED (or laser diode) driver

- □ Laser diode (LD) illumination possible
- □ Open-drain LED output pad, up to 200mA drive
- □ Push-pull LED2 output pad, up to 50mA drive

#### ■ Parallel digital data interface TCMI

- □ 80MS/s max. data rate, 2.5/3.3V compatible
- □ 12/8-bit DATA output + XSYNC/SAT flag on 8 bit parallel TCMI interface.
- USYNC, HSYNC and DCLK outputs

### ■ I<sup>2</sup>C control interface (slave)

□ 400kHz (FM) / 1MHz (FM+)

### ■ Integrated EEPROM 128 x 8-bit

- □ Calibration data and user programmable parameters
- □ Unique chip ID

#### ■ System / Modulation clock

- □ System clock 4MHz, internal by using crystal/resonator or using external input
- External LED/LD modulation input MODCLK (optional) up to 80MHz

#### ■ Power supplyø

- □ Supply voltages +10V, +5V, +2.5/3.3V, +1.8V, -10V
- □ Power consumption approx. 300mW (average)

### ■ Packaging

- □ 6.3x4.2mm cost optimized 44pin CSP (chip scale package),
- □ Backside illuminated flip-chip SMD mounting

### ■ Other data

□ ROHS compatible

### **Measurement Modes**

#### ■ Illumination modulation modes

- □ Sinusoidal modulation
- □ Selectable modulation frequencies 0.625 ... 20MHz resulting in unambiguity distance of 7.5m ... 240m

### ■ Distance measurement modes

- □ 128 fps 3D TOF with 4x DCS frames, full pixel-field
- □ 256 fps 3D TOF with 2x DCS frames, full pixel-field
- □ 512 fps 3D TOF with rolling read-out 4x DCS frames, full pixel-field
- □ SHUTTER release input for precise start/stop and single / continuous measurement control

#### ■ Non distance measurement modes

- □ Ambient-light measurement (Grayscale imaging without illumination)
- □ Grayscale image with active illumination

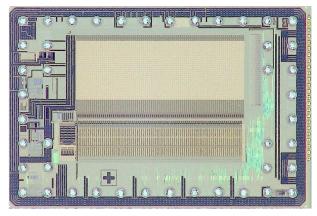


Figure 2: Picture of the epc635 die

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# 1. Electrical, optical and timing characteristics

All characteristics are at typical operational ratings, T<sub>A</sub> = +25°C, modulation frequency 10MHz, unless otherwise stated

### 1.1. Operating conditions and electrical characteristics

Parameter	Description	Conditions/Comments	Min.	Тур.	Max.	Units
$V_{DD}, V_{DDPLL}$	Digital supply voltage	Ripple <sup>1</sup> < ± 20 mV	1.71	1.80	1.98	V
V <sub>DDIO</sub>	IO supply voltage <sup>3</sup>	Ripple <sup>1</sup> < ± 50 mV	2.25	2.5/3.3	3.63	V
$V_{DDA}$	Analog 1 supply voltage <sup>2</sup>	Ripple <sup>1</sup> < ± 20 mV	4.9	5.0	5.1	V
$V_{DDPXH}$	Analog 2 supply voltage <sup>2</sup>	Ripple <sup>1</sup> < ± 20 mV	9.5	10	10.5	V
V <sub>BS</sub>	Bias supply voltage	Ripple <sup>1</sup> < ±50 mV	-10.5	-10.0	-9.75	V
I <sub>VDD</sub>	Digital supply current	@nominal voltage		10	11	mA
I <sub>VDDPLL</sub>	PLL supply current	@nominal voltage		4		mA
I <sub>VDDIO</sub>	IO supply current <sup>4</sup>			15	25	mA
I <sub>VDDA</sub>	Analog supply current	@nominal voltage		22	33	mA
I <sub>VDDPXH</sub>	Analog 2 supply current	@nominal voltage		2	2	mA
I <sub>VBS</sub>	Bias supply current 8			-2.0 <sup>8</sup>		mA
V <sub>LED_ON</sub>	LED on-voltage forward voltage	@ I <sub>LEDOD-ON</sub> = 100 mA @ I <sub>LEDOD-ON</sub> = 200 mA		0.1 0.2		V
I <sub>LED_LEAK</sub>	LED leakage current	@ LEDOD off-voltage			10	μA
I <sub>LED2_SINK</sub>	LED2 output sink/source current				50	mA
V <sub>IH_VDDIO</sub>	Digital high level input voltage ⁵	excluding XTALIN	0.7 x V <sub>DDIO</sub>			V
V <sub>IL_VDDIO</sub>	Digital low level input voltage 5	excluding XTALIN			0.3 x V <sub>DDIO</sub>	V
V <sub>IH_XTALIN</sub>	Digital high level input voltage	XTALIN	1.35			V
V <sub>IL_XTALIN</sub>	Digital low level input voltage	XTALIN			0.2	V
V <sub>OH</sub>	Digital high level output voltage 5,6		0.8 x V <sub>DDIO</sub>			V
V <sub>OL</sub>	Digital low level output voltage 5,6				0.2 x V <sub>DDIO</sub>	V
R <sub>PD</sub>	Pull-down resistor in RESET, VSYNC_A0, HSYNC_A1			600		kΩ
I <sub>IH</sub>	Digital high level input current <sup>7</sup>	V <sub>IH</sub> max.			10 <sup>7</sup>	μA
I <sub>IL</sub>	Digital low level input current 7	V <sub>⊩</sub> min.	-10 <sup>7</sup>			μA
I <sub>OH</sub>	Digital output source current 7	V <sub>OH</sub> max.			50	mA
I <sub>OL</sub>	Digital output sink current <sup>3</sup>	V <sub>OL</sub> min.	-50			mA
C <sub>IO</sub>	IO load capacitance 5				30	pF
f <sub>IO</sub>	IO switching frequency 5			20	80	MHz
P <sub>Pk</sub>	Power dissipation (average)	See Table 30		300		mW
R <sub>Th</sub>	Thermal resistance	on PCB with underfill			40	°K/W
T <sub>OP</sub>	Operating temperature		-40		105	°C

Table 1: Operating conditions and electrical characteristics

#### Notes:

<sup>&</sup>lt;sup>1</sup> Min. and Max. voltage values include noise and ripple voltages.

<sup>&</sup>lt;sup>2</sup> Analog voltage supplies have direct influence on measurement performance. They must be properly decoupled for low noise and ripple.

<sup>&</sup>lt;sup>3</sup> IO voltage supply must be equal to external processor's IO supply voltage levels used in the application. It can be set to any value within min and max. operating voltage.

<sup>&</sup>lt;sup>4</sup> When device is operated at max f<sub>DCS</sub> frame rate, DCLK at 40MHz, driving loads 15pF each.

<sup>&</sup>lt;sup>5</sup> I<sup>2</sup>C pins SCL and SDA are open-drain outputs and need termination (Pull-up resistor) according to I<sup>2</sup>C standards.

 $<sup>^6~~</sup>V_{\text{OH/OL}}$  and  $I_{\text{OH/OL}}$  values are measured at max  $C_{\text{IO}}$  and max  $f_{\text{IO}}.$ 

<sup>&</sup>lt;sup>7</sup> Value is without termination resistors

A bright illuminated white target right in front of the chip with lens leads to an I<sub>VBS</sub> of approx. -2.0 mA, without any illumination approx. -2.0 mA and with strong illumination (approx. 55 mW/cm², no lens) typ. -9.0 mA.

## 1.2. Absolute maximum ratings

Parameter	Conditions
Supply voltage V <sub>DD</sub> , V <sub>DDPLL</sub>	-0.5V +2.0V
Supply voltage V <sub>DDIO</sub> , V <sub>DDA</sub> , V <sub>DDPXM</sub>	-0.5V +5.5V
Supply voltage V <sub>DDPXH</sub>	-0.5V +13.5V
Supply voltage V <sub>BS</sub>	-12.0 +0.5V
Voltage to any pin in the same V <sub>sc</sub> supply class.	V <sub>SC min</sub> - 0.3V V <sub>SC max</sub> + 0.3V
LED sink current I <sub>ON_LED</sub> (modulated peak current, refer to Figure 16)	200 mA @T <sub>J</sub> 85°C 25 mA @T <sub>J</sub> 125°C linear reduction between 85 and 125°C
LED off-voltage V <sub>OFF_LED</sub> (open-drain output)	7.5 V
ESD rating	JEDEC HBM class 1C (1kV to < 2kV)
Junction temperature (T <sub>J</sub> )	-40°C to +125°C
Relative humidity	0 95%, non-condensing

Table 2: Absolute maximum ratings

### 1.3. Timing parameters

Parameter	Description	Conditions	Min.	Тур.	Max.	Units
t <sub>STARTUP</sub>	Start-up time	after applying external supplies		340	1'000	μs
t <sub>RESET</sub>	RESET		100			ns
t <sub>PLL</sub>	PLL lock time				30	μs
t <sub>DLL</sub>	DLL delay for 1 step	approx. 30cm distance shift per step. Refer for details to register 0x73 and Figure 20, for exact value to register 0xE9.		2.1		ns
t <sub>DRV</sub>	Illumination driver delay	delay of LED/LED2 versus demodulation, refer to Figure 20		8.4		ns
t <sub>EEPROM_to_CFG</sub>	Load CFG registers	copy EEPROM to CFG registers		340		μs
t <sub>EEPROM_Write</sub>	Write EEPROM	waiting time per byte			25	ms
f <sub>XTAL</sub>	Clock frequency	determines the distance measurement accuracy	3.8	4	4.2	MHz
df <sub>XTAL</sub>	Clock frequency deviation	any deviation is added as a linear distance error			±100	ppm
f <sub>JITTER</sub>	Clock frequency phase jitter	peak-to-peak, cycle to cycle			50	ps
f <sub>LED</sub>	LED modulation frequency		0.625		20	MHz
f <sub>MODCLK</sub>	Ext. modulation clock	refer to chapter 5.5.			80	MHz
t <sub>LED_rise/fall</sub>	Rise/fall time LED/LD	slower rise/fall time lead to illumination losses			12	ns
f <sub>DCLK</sub>	TCMI DCLK	8 bit TCMI data + saturation flag		20	80	MHz
f <sub>TCMI_data</sub>	TCMI data rate			130	520	Mbit/s
f <sub>SCL</sub>	I <sup>2</sup> C data rate				1	Mbit/s

Table 3: Timing parameters

# 1.4. Optical characteristics

Parameter	Description	Conditions/Comments	Min.	Тур.	Max.	Units
A <sub>PIXEL</sub>	Pixel photosensitive area	100% fill factor		20 x 20		μm
A <sub>SENSOR</sub>	Pixel field area	160 x 60 pixel		3.2 x 1.2		mm

Table 4: Optical characteristics

#### Note:

Values depend on camera integration. Typical examples only. Refer for details to Figure 20 and application note AN10 Calibration and Compensation, chapter temperature compensation.

### 1.5. Sensitivity

@ integration time 100 µs

Parameter	Description		Min.	Тур.	Max.	Units
	Modulation frequency 12MHz		0.75	0.9	1.05	2
TOF sensitivity S <sub>TOF</sub>	Amplitude 1,400 LSB	850nm	0.50	0.6	0.70	nW/mm² LSB
		940nm	0.65	0.8	0.95	
TOF <sub>SENS</sub> FPN	Sensitivity fix pattern noise, @ 1,400 LSB			40	100	LSB
TOF <sub>DIST</sub> FPN	Distance fix pattern noise, @ 1,400 LSB			18	50	mm
Dark	Dark current (drift during readout)			10	20	LSB/ms
	Normal operation			0.25	0.31	nW/mm²
Grayscale sensitivity	Temperature sensing mode			0.62	0.76	LSB
Η <sub>ν</sub>	Optical sensitivity			150k		LSB Lux/sec
GS <sub>STD</sub>	Grayscale standard deviation			25	100	LSB

Table 5: Sensitivity

### 1.6. Ambient-light suppression (ABS)

An important function of the 3D TOF pixel is the ambient-light suppression. It removes DC or low frequency modulated light caused by sunlight, room illumination, etc. from the modulated light generated by the camera illumination. The amount of collected ambient light is proportional to the integration time. The longer the integration time, the more unwanted light will be collected. It's a good practice to keep the integration time for TOF imaging below 1ms. In addition, optical bandpass filters to block the unwanted light spectrum is mandatory.

Parameter	Ambient light suppression	Integration time	Wave- length	Min.	Тур.	Max.	Units
E <sub>e</sub>	Irradiance, DC light	100 µs	640nm	0.30			mW/mm²
			850nm	0.20			
			940nm	0.25			

Parame	ter Ambient light suppression	Integration time	Center wavelength	Bandwidth	Min.	Тур.	Max.	Units
E,	Luminance equivalent, sunlight	500µs	640nm	±27.5nm	85			kLux
			850nm	±32.5nm	70			
			940nm	±30nm	190			

Table 6: Ambient light suppression

### Note:

The default and suggested chip configuration is set to achieve highest possible frame rate and using additional ambient-light correction according the Application note AN10 Calibration and compensation: Register 0x90, bit 3 = 0 and 0xAB = 0x00. A 20% more efficient ambient-light suppression is possible, if the the following registers are modified:

0x90, bit 3 = 10xAB = 0x01

It turns the LED modulation before each integration for additional 33 $\mu$ s @ 24MHz modulation frequency on. This modulation is independent of the effective integration time. The on-time depends on the modulation frequency by  $t_{ON}$  = 40 $\mu$ s \* 20MHz / modulation frequency.

# 1.7. Other optical parameters

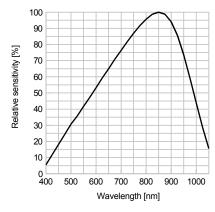


Figure 3: Relative spectral sensitivity  $(S_{\lambda})$  vs. wavelength

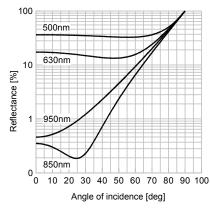


Figure 4: Reflectance vs. illumination angle (AOI)

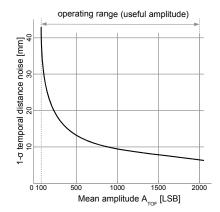


Figure 5: Typ. distance noise, single shot, 4 DCS, no ambient-light, see chapter 9.2.2.

### 1.8. Temperature sensor characteristics

Parameter	Description	Conditions	Min.	Тур.	Max.	Units
T <sub>TEMP</sub>	Measurement range		-40		+105	°C
P <sub>TEMP</sub>	Sensor resolution			14		bit
k	Temperature sensor gain			0.067		K/LSB
Lin	Linearity	Over temperature range		5		%
T <sub>CAL</sub>	Calibration temperature		26.5	27.0	27.5	°C

Table 7: Temperature sensor characteristics

Note: Refer also to chapter 10.

### 1.9. Distance measurement temperature drift

@12MHz modulation frequency

	, ,				
Parameter	Description	Min.	Тур.	Max.	Units
TC <sub>PIX</sub>	Pixel		12.9		mm/K
TC <sub>OD</sub>	LED/LD driver		2.7		mm/K
TC <sub>DLLn</sub>	DLL stage, per stage		0.65		mm/K

Table 8: Optical characteristics

Note: Values vary from imager to imager. Refer for details to Figure 20 and application note AN10 Calibration and Compensation, chapter temperature compensation.

# 2. Pin-out

## 2.1. Pin mapping

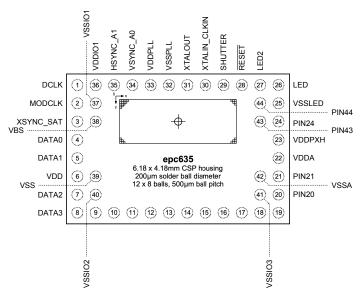


Figure 6: Pin mapping (top-view, solder balls are at the bottom, pixel-field is at the top)

#### 2.2. Pin list

Pin No.	Pin name	Supply	Pin type	RESET function	RESET level	Description
		V <sub>sc</sub>	, ·			
IO pi	ns					
4	DATA0	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI high-speed output bit 0 (LSB), no pull-up resistor allowed
5	DATA1	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI high-speed output bit 1
7	DATA2	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI high-speed output bit 2
8	DATA3	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI high-speed output bit 3
10	DATA4	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI high-speed output bit 4
11	DATA5	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI high-speed output bit 5
12	DATA6	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI high-speed output bit 6
13	DATA7	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI high-speed output bit 7
1	DCLK	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI data clock output
34	VSYNC_A0	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OH</sub>	TCMI VSYNC output / strap input 0, refer to 5.6.3.
35	HSYNC_A1	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OH</sub>	TCMI HSYNC output / strap input 1, refer to 5.6.3.
3	XSYNC_SAT	$V_{\text{DDIO}}$	DIO	IPD	V <sub>OL</sub>	TCMI XSYNC / TCMI Saturation flag output, no pull-up resistor allowed
18	SCL	$V_{\text{DDIO}}$	DIOD	I	V <sub>IH</sub>	I <sup>2</sup> C clock input <sup>4</sup>
19	SDA	$V_{\text{DDIO}}$	DIOD	I	V <sub>IH</sub>	I <sup>2</sup> C data input/output <sup>4</sup>
29	SHUTTER	$V_{\text{DDIO}}$	DI	PD	V <sub>IL</sub>	Shutter release input
28	RESET	$V_{\text{DDIO}}$	DI	PD	V <sub>IL</sub>	Reset input (active low), 600kΩ int. pull-down <sup>3</sup>
2	MODCLK	$V_{\text{DDIO}}$	DI	PD		Modulator/demodulator external clock input.
27	LED2	$V_{\text{DDIO}}$	DO		V <sub>IL</sub>	LED driver push-pull output <sup>2</sup>
14	PIN14	$V_{\text{DDIO}}$	DO		V <sub>OL</sub>	
15	PIN15	$V_{\text{DDIO}}$	DI	PU	V <sub>IH</sub>	Do not any electrical connection except to a test pad (suggested).
16	PIN16	$V_{\text{DDIO}}$	DI	PD	V <sub>IL</sub>	Do not any electrical conflection except to a test pad (suggested).
17	PIN17	$V_{\text{DDIO}}$	DI	PU	V <sub>IH</sub>	
Digit	al pins					
30	XTALIN_CLKIN	$V_{\text{DDPLL}}$	Al			XTAL or Resonator in / CLKIN from external clock source
31	XTALOUT	$V_{\text{DDPLL}}$	AO			XTAL or Resonator out
Anal	og pins					
26	LED	$V_{\text{DDLED}}$	AOD		V <sub>LED</sub>	LED/LD driver open-drain output <sup>2</sup>
24	PIN24	$V_{DDLED}$	Al			
20	PIN20	$V_{DDA}$				Connect to VSSA with 10 kOhm
21	PIN21	$V_{DDA}$				
43	PIN43	$V_{DDPXH}$	Al			Do not any electrical connection except to a test pad (suggested).
44	PIN44	$V_{DDPXH}$	Al			The first any electrical conflection except to a test pad (suggested).

Pin No.	Pin name	Supply class V <sub>sc</sub>	Pin type	RESET function	RESET level	Description
Supp	oly pins, digital					
36	VDDIO1	$V_{\text{DDIO}}$	PWR			IO supply VDDIO
9	VDDIO2	$V_{DDIO}$	PWR			
6	VDD	$V_{DD}$	PWR			Digital supply VDD
33	VDDPLL	$V_{DDPLL}$	PWR			PLL supply
37	VSSIO1	$V_{DDIO}$	GND			
40	VSSIO2	$V_{DDIO}$	GND			IO ground VSSIO
41	VSSIO3	$V_{DDIO}$	GND			
39	VSS	$V_{DD}$	GND			Digital ground VSS
32	VSSPLL	$V_{DDPLL}$	GND			PLL ground
Supp	oly pins, analog					
22	VDDA	$V_{DDA}$	PWR			Analog supply VDDA
38	VBS	$V_{BS}$	PWR			Bias supply
23	VDDPXH	$V_{DDPXH}$	PWR			Analog 2 supply VDDPXH
42	VSSA	$V_{DDA}$	GND			Analog ground VSSA
25	VSSLED	$V_{DDLED}$	GND			LED/LD driver ground (return current) <sup>1</sup>

Table 9: Pin list

#### Notes:

- <sup>1</sup> VSSLED is the dedicated, isolated GND pin for the LED/LD return-current from external circuitry. It must be connected to PCB GND plane together with the other VSSA GND pins.
- <sup>2</sup> LED output can be used to drive an external amplifier with an addition of a pull-up resistor. The voltages at LED output must not exceed values in Table 1: Operating conditions and electrical characteristics.
  - LED2 output is a push-pull driver for delivering symmetric rise/fall times to the external LED driver circuit. LED2 is internally connected to VDDIO/VSSIO supplies. During integration time, all TCMI pins are silent except for DCLK. As a result, LED2 pin will not pick up switching noise from all other TCMI pins. This can be avoided by using gated DCLK mode.
  - LED and LED2 must not be used simultaneously for driving LED circuits on the PCB. They exhibit different insertion delays and may cause unpredicted distance offset/measurement results.
- <sup>3</sup> RESET pin has a 600kΩ (typical) internal pull-down resistor. Therefore, this pin can be safely connected to a standard GPIO of a CPU which is initially high-Z or open-drain during power-up sequence. Once the SW takes control, it can program this GPIO as output and drive 1 to release the RESET. The internal pull-down can be override by and external 10kΩ pull-up and a series capacitor to build a simple delayed power-on reset for evaluation/qualification purposes.
- <sup>4</sup> l<sup>2</sup>C pins SCL, SDA are according to l<sup>2</sup>C standards. They are l<sup>2</sup>C slave pins which need external pull-up resistors on the PCB. Values of R1 and R2 in the schematics are given only for indicative purposes and must be re-calculated according to the total capacitive load of all l<sup>2</sup>C slave/master devices and operating mode (FM or FM+) of the l<sup>2</sup>C (chapter 13.) in the application.

'Pin type' in Table 9 defines the following:

■ DI: Digital Input

■ DO: Digital Output

■ DIO: Digital Input/Output (bidirectional)

■ DIOD: Digital Input/Output (bidirectional), open-Drain

■ Al: Analog Input■ AO: Analog Output

■ AOD: Analog Output, open-Drain

■ PWR: Supply ■ GND: Ground

'RESET function' in Table 9 defines the function of IO pins during reset:

■ I: Input

■ PU: internal Pull-Up■ PD: internal Pull-Down

■ IPD: Input with internal Pull-Down

'RESET level' in Table 9 defines the level of the IO pins during/after reset (chapter 5.6.)

### 2.3. Power domains and ESD protection

The epc635 chip has internally 7 different power domains and 5 ground references which are interconnected with ESD protection diodes. All pins are also equipped with ESD protection diodes. The diodes have a breakthrough voltage of 0.3V. The designer has to take care that none of these diodes become conductive either at power-up, power-down or normal operation.

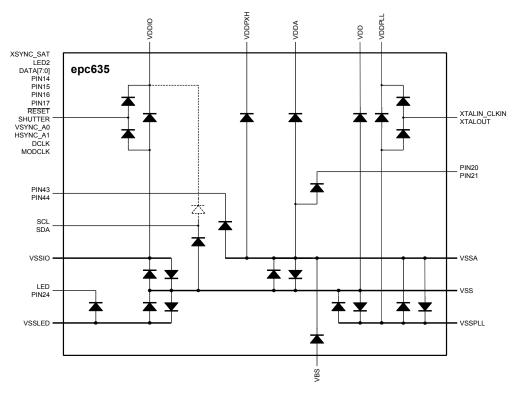


Figure 7: I/O pins and ESD protection diagram

# 3. Packaging and layout information

### 3.1. Mechanical dimensions

#### Top side view 3.200 (0.350)Pin 1 163 2 5 34 (33) (32) (31) (30) (29) (1)(36) 35 28 27 26 3.500 (8 bumps with 0.5mm pitch) 44 25 37 R6 1.600 epc635 pixel-field 160 x 60 pixel 0.5001.200 24 (3) 38 43 18 +0.00/-0.08 Pixel size: 20µm x 20µm R65 Top side 23 4 (5) 22 Solder balls (6) (39) 21 42 (41) 20 9 10 11 12 13 | 14 15 16 17 18 19 (0.430)0.19 ±0.02 (0.050)0.500 2.700 5.500 (12 bumps with 0.5mm pitch) 6.26 +0.00/-0.08

Figure 8: Mechanical dimensions

#### Notes:

- • •
- all measures in mm
- not specified tolerances: ±0.001mm
- Top side is illumination side

### 3.2. Parasitic light sensitivity (PLS)

CMOS circuits are sensitive to light. That is why they can be used for photo-sensing, imaging, etc. However, if strong light is radiating the chip beside the pixel field, analog and digital circuits can be affected in its function by such parasitic light. It is called parasitic light sensitivity (PLS). A known effect is a shift of the measured distance under strong ambient light.

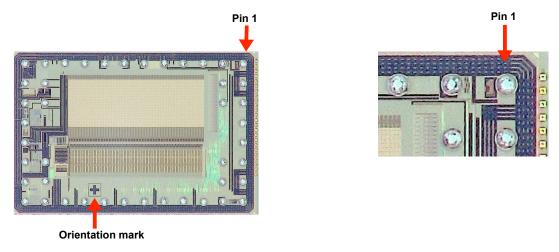
Imager lenses have always a larger field of view than the pixel-field area. In order to prevent the chip being illuminated by strong ambient light, an opaque aperture should be placed onto the photosensitive side of the imager as shown in Figure 9. The cover shall have a opening of  $3.490 \times 1.490$  mm. With regard to the  $3.200 \times 1.200$  mm pixel-field size, this shield can be assembled with a tolerance of  $\pm 120 \ \mu m$  in x and y axis. Such a cover can be made by a thin sheet metal stencil like an SMD solder paste printing stencil or by silk screen printing of black color.

#### Top side view Opening: 3.490 ±0.050 Minimize gap to reduce 3.200 stray-light underneath Pin 1 (0.350)the cover 163 2 $\overline{c}$ 36 33 (31) 30 29 26 (1) 34 32 27 37 44 25 R6 900 200 Photosensitive area 3 (38) 43 24 on top side 18 +0.00/-0.08 R65 23 Тop 5 22 Opening: 1.490 ±0.050 6 39 21 41 20 40 9 (11) (13) (14) (15) 19 (0.430)2.700 Light absorbing cover with opening at pixel-field, Chip size: 6.26 +0.00/-0.08 nor reflective nor transparent, blocking ambient-light surrounding the pixel-field

Figure 9: Opaque cover for protection against unwanted ambient-light

#### 3.3. Pin1 marking

The following pictures shows the epc635 chip from the bottom side with view to the solder balls. Please note the location of pin 1. It's highly recommended to check the pin 1 location with a vision system during the SMT assembly process.



epc635 chip from the solder ball side

Top right corner from the solder ball side

Figure 10: Pin 1 marking

#### 3.4. Location of the photosensitive area

The photosensitive area is not marked (neither on the front nor on the backside of the IC). As a visible reference, a metal ring of the IC can be used. From the solder ball side it is visible. Also from the front side (photosensitive area) it can be seen with a camera which is sensitive in the near infrared wavelength domain (950 .. 1'150nm).

#### 3.5. PCB design and SMD manufacturing process considerations

As the epc635 chip comes in a 44 pin chip scale package with only 50µm thickness, the PCB layout should be made with special care. In addition, careful handling during the assembly process shall be assured in order to avoid mechanical damage during the assembly process. Because the silicon chip is small and light weight compared the solder balls, it is highly recommended that all tracks to the chip should come straight from the side. A symmetrical design is highly recommended to achieve high production yield. The pads and the tracks should also have exactly the same width at least for 1mm from the pad. They shall be covered by a solder resist mask in order to avoid drain of the solder tin alloy to the track.

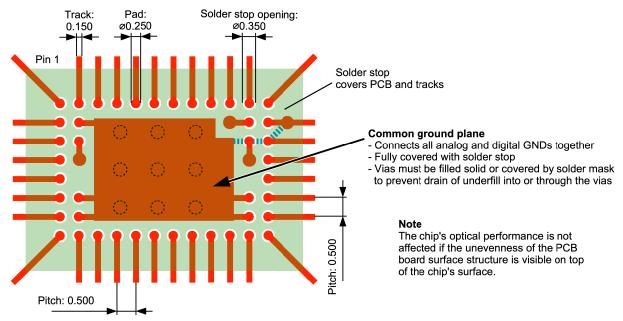


Figure 11: Recommended PCB layout (all measures in mm)

As shown in Figure 11, a ground plane shall be placed on the top PCB layer underneath the chip. This ground plane acts as a shield to suppress high frequency emission of fast interface signal lines. It is important that this plane is completely flat. Thus, the plane must not be scattered nor divided into sections. It should be rather full-faced and no via should be placed in this plane. Otherwise chip bending might occur.

Underfill of the components reduces stress to the solder pads caused by e.g. temperature cycling or mechanical bending. Furthermore the thermal and mechanical fatigue will be reduced and the longterm reliability will be increased. Underfill material and underfill selection is application specific. It shall follow JEDEC-STD JEP150: Stress-Test-Driven Qualification of and Failure Mechanisms Associated with Assembled Solid State Surface- Mount Components. Please also, refer to the application note AN08 Process-Rules CSP Assembly which

can be downloaded from the ESPROS Website at www.espros.com, section Downloads. Obeying these recommendations a high manufacturing yield can be achieved.

### 3.6. Tape & reel information

The devices are mounted on embossed tape for automatic placement systems. The tape is wound on 178 mm (7 inch) or 330 mm (13 inch) reels and individually packaged for shipment. General tape-and-reel specification data are available in a separate data sheet and indicate the tape sizes for various package types. Further tape-and-reel specifications can be found in the Electronic Industries Association (EIA) standard 481-1, 481-2, 481-3.

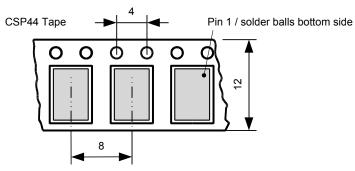


Figure 12: Tape dimensions (all measures in mm)

ESPROS does not guarantee that there are no empty cavities. Thus, the pick-and-place machine should check the presence of a chip during picking.

# 4. Ordering information

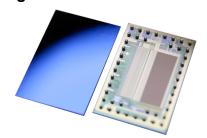


Figure 13: epc635-CSP44, top and bottom side



Figure 14: epc635 Card Edge Connector Carrier, refer to separate datasheet

Part Number	Part Name	Package	RoHS compliance
P100 181	epc635-CSP44	CSP44	Yes
P100 404	epc635 Card Edge Connector Carrier	PCB 37.25 x 36.00 mm	Yes

Table 10: Ordering Information

### 4.1. Notes to various chip releases

The supplied chip version can be identified by

- reading the extension -XXX of the part name on the packaging labels or delivery papers: epc635-CSP44-XXX.
- reading the part version register 0xFB: Refer to chapter 15.10.
- The latest download code for each chip version is included in the download package for the epc660 Evaluation Kit (see chapter 15.10).

# 5. Hardware implementation

## 5.1. Typical application diagram

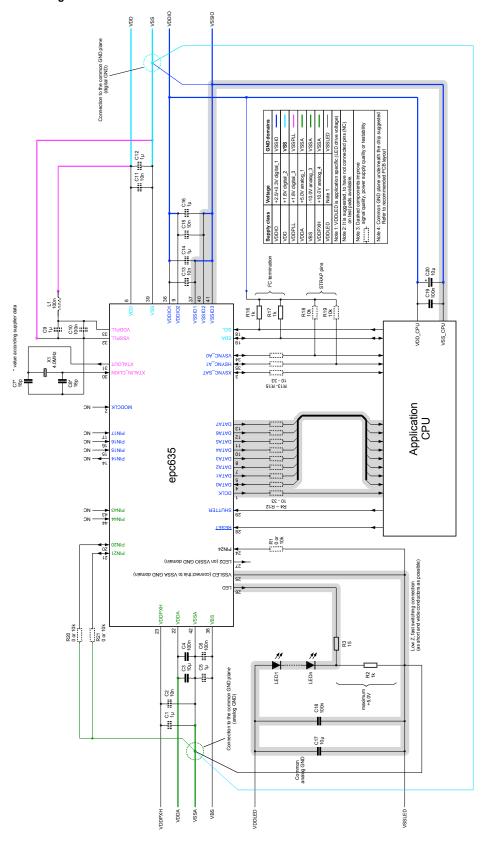


Figure 15: Typical application diagram

Notes: R4 -R15: R1, R20, R21: R18, R19:

Resistor value depends on fast bus decoupling. Pins need to be connected to corresponding GND. In case of need to testability: use 10k resistors.

Resistor value depends of needed strap function.

#### 5.2. Application diagram part list

Part	Description	Pin No.		Value		Toler-	Supply	Comments
designator			Min.	Тур.	Max.	ance	class V <sub>sc</sub>	
Minimum par	t count:		<u> </u>					
C3	VDDA	22 - 42	4.7 µF	10 µF		±20%	V <sub>DDA</sub>	Ceramic X7R
C4	VDDA	22 - 42		100 nF		±20%	V <sub>DDA</sub>	Ceramic X7R
C7, C8	XTAL	30 – 32, 31 - 32		18 pF <sup>2</sup>		±20%	V <sub>DDPLL</sub>	Ceramic NPO
X1	XTAL	30 - 31		4 MHz		±100ppm	V <sub>DDPLL</sub>	Quartz / Resonator
R4 - R15	Bus termination		0 Ohm	10 Ohm	33 Ohm	±20%	V <sub>DDIO</sub>	Resistors
R16, R17	I <sup>2</sup> C pull-up			1 kOhm		±20%	V <sub>DDIO</sub>	Resistors
R18, R19	I <sup>2</sup> C address			10 kOhm		±20%	V <sub>DDIO</sub>	Resistors
Dashed comp	ponents improve	signal quality, power su	upply quality or	testability				
C1	VDDPXH	23 - 42	1 µF			±20%	V <sub>DDPXH</sub>	Ceramic X7R
C5	VBS	38 - 42	1 µF			±20%	V <sub>BS</sub>	Ceramic X7R
C9	VDDPLL	33 - 32	1 µF			±20%	V <sub>DDPLL</sub>	Ceramic X7R
C12	VDD	6 - 39	1 µF			±20%	V <sub>DD</sub>	Ceramic X7R
C14, C16	VDDIO	36 – 37, 9 - 40	1 µF			±20%	V <sub>DDIO</sub>	Ceramic X7R
C6	VBS	38 - 42		100 nF		±20%	V <sub>BS</sub>	Ceramic X7R
C22	VDDPLL	61 - 62		100 nF		±20%	V <sub>DDPLL</sub>	Ceramic X7R
C2	VDDPXH	22 - 42		10 nF		±20%	V <sub>DDPXH</sub>	Ceramic X7R
C11	VDD	6 - 39		10 nF		±20%	V <sub>DD</sub>	Ceramic X7R
C13, C15	VDDIO	36 – 37, 9 - 40		10 nF		±20%	V <sub>DDIO</sub>	Ceramic X7R
L1	VDDPLL			100 nH		±20%	V <sub>DDPLL</sub>	Inductor

Table 11: Values of component related to epc635 chip, seeFigure 15

#### Notes:

- <sup>1</sup> All other components are application specific.
- <sup>2</sup> The capacitor value has to be selected according the crystal or resonator supplier's recommendation

#### 5.3. Hardware implementation notes

- 1. Decoupling capacitors must be placed as close as possible to their supply pin pair in order to minimise ripple on the supply rails due to fast switching high-speed signals (Table 11).
- 2. +1.8V is used for supplying the digital logic (VDD), the on-chip oscillator OSC and the phase-look-loop PLL (VDDPLL). The digital logic creates some internal switching noise on VDD. When the same supply is shared together with OSC and PLL, their supply wiring must be separated from the digital wires and physically isolated from each other. These supplies are marked in the application diagram as VDD and VDDPLL respectively (Figure 15). A good practice is inserting on the PCB a series inductance of 100nH between them close to the supply source, then creating separate supply islands for both on the board. The XTAL/OSC and PLL are critical parts of the chip which directly impacts the optical system performance (i.e. distance calculation).
- 3. +2.5/3.3V is used for supplying the high-speed IO pins (MODCLK, TCMI and LED2) and the slow I²C pins (VDDIO). High speed IO pins toggle at 10/20/40/80MHz during data transfer, hence generating continuously switching noise (much more dominant than the digital noise). Therefore VDDIO supply wires and layers must be carefully designed and isolated in a separate supply island on the PCB. It is not recommend to change this voltage on the fly when the TCMI, LED2 or I²C interfaces are running. When the application needs power saving during system idle periods, it can be scaled from +3.3V down to +2.5V only after frame acquisition is stopped and both interfaces are completely inactivated. It can be increased back to +3.3V before re-activating the chip for frame acquisition, accessing I²C, LED2 or TCMI interface. Note that, voltage scaling must be done in a controlled way having both application CPU's and epc635's IO voltages at the same time at the same level.
- 4. +5V is used for supplying analog blocks of the chip e.g. pixel-field drivers and ADC readout circuitry. Refer to Figure 15.
- 5. +10V is used for supplying pixel-field circuitry (VDDPXH).
- -10V (VBS) is used for biasing the the pixel-field like reverse-biasing a photodiode. The use of a stable supply source with a low ripple
  is recommended. There is no switching or active internal circuit dependent current consumption, except ambient-light dependent leakage current (refer to Table 1, note 8).
- A 4MHz quartz crystal or a ceramic resonator is connected to XTALIN\_CLKIN and XTALOUT pins in order to use internal oscillator OSC as time base for the epc635. The frequency accuracy and stability are directly related to the distance readings. Alternatively an external clock source can be used (chapter 5.4.).
- 8. MODCLK input can be used for user controlled/modulated clock. It is used for both the LED driver and the pixel-field demodulator.
- 9. SCL, SDA are I<sup>2</sup>C slave pins which need external pull-up resistors on the PCB (see also VDDIO supply). Values of R16 and R17 are given only for indicative purpose and must be re-calculated according to the total capacitive load of all I<sup>2</sup>C slave/master devices and the operating mode FM or FM+ of the I<sup>2</sup>C (chapter 13.) in the application.

- 10. VSYNC\_A0, HSYNC\_A1, XSYNC\_SAT, DATA[11:0], DCLK, high-speed TCMI signals (chapter 6.), SHUTTER and RESET control signals toggle in the VDDIO range. To minimize the skew, the high-speed \*SYNC, DATA[11:0], DCLK signals wires must be routed equal in impedance and length less than 10cm long with less than 10mm difference on the PCB. As they are toggling all the time, they can be separated with ground wires on the side adjacent to other signals/supply lines, routed with enough distance from other sensitive signal wires on the board. Series termination resistors R4 ... R15 (10 ... 33Ω) are needed at high-speed outputs to control the slew
- 11. Optional pull-up resistors R18 and R19 ( $10k\Omega$ ) set initial values of some configuration registers during start up of the chip. Such outputs pins are called strap pins. They are scanned one time immediately after RESET is released (chapter 5.6.3.).
- 12. The LED pin is an open-drain LED/LD driver output. When the driver is active (on), the LED/LD on-current flows through the power resistor R3 into the LED pin, through the driver and comes out of the chip on the VSSLED ground pin. The LED pin toggles up to 20MHz or according to the MODCLK clock with a current maximum of 200mA limited by the resistor R3. The number of IR LEDs depends on the level of the LED supply voltage and the turned-on forward voltage drop of the IR LEDs. This signal creates a lot of ground noise. Therefore, VSSLED pin is decoupled from the other analog grounds internally. It must be shorted with the other analog ground pins with a low-ohmic connection as short as possible on the PCB. In this way, there will be minimal voltage differences in the ground planes of the board. The LED supply line must be isolated properly from any analog supply on the PCB to minimize noise coupling from the LED drivers.

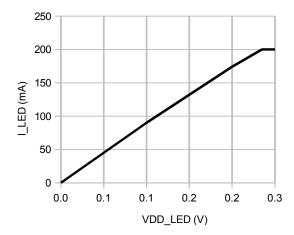


Figure 16: Output characteristic I $_{\text{LED}}$  versus  $V_{\text{DDLED}}.$  Refer for maximum values of  $V_{\text{DDLED}}$  and  $I_{\text{LED}}$  to Table 1 and Table 2

- 13. The LED2 pin is the alternative push-pull driver providing symmetric rise/fall times to drive external LED driver. It works from the +2.5/+3.3 VDDIO supply (VSSIO GND domain) and swings in the same voltage range like the TCMI pins. LED2 = LOW (approx. 0V) corresponds to LED = OFF (max. output voltage). LED and LED2 pins must not be used at the same time for driving the external illumination. They exhibit different phase delays and this can result wrong distance measurements. None of the TCMI pads toggle during integration time, LED2 pin is the only toggling during integration time and it is not affected from switching noise of others.
- 14. It is recommended having "not connected pins" (PINxx) on test pads available. It helps e.g. to check after assembly for correct orientation of the chip or for short-cuts.
- 15. Pins not listed here have to be connected according Figure 15.

#### 5.4. Clock source

Instead of a crystal, an external 4MHz clock source can be connected to the XTALIN\_CLKIN pin. XTALOUT output pin left unconnected. Input clock signal levels must match V<sub>DDPLI</sub>/V<sub>SSPLL</sub> supply levels (Table 1). If the external clock source comes from the +2.5/3.3V voltage domain, a resistor divider circuit can be deployed to adjust the voltage level according to Figure 17.

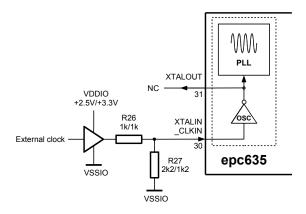


Figure 17: Resistor divider to adjust external clock voltage levels to XTALIN\_CLKIN

**IMPORTANT:** The optical performance of the chip directly depends on the input clock precision/stability. XTALOUT must not be used to drive external loads.

#### 5.5. External modulation MODCLK

The epc635 has for enhanced user applications the possibility to bring an external modulation clock to the chip. The optional MODCLK input can be used to inject a user controlled/modulated clock for both the LED driver and the pixel demodulator, see Figure 18.

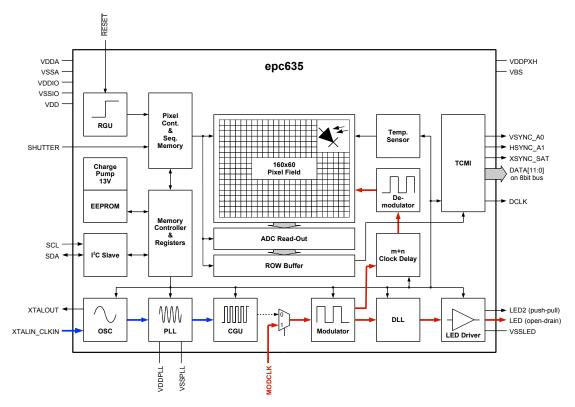


Figure 18: The MODCLK signal flow (red marked)

The external MODCLK can be used e.g. in concepts for reliable multi camera applications. It allows to use e.g. frequency-division multiple access (FDMA). In corresponding literature, the details of these concepts are explained in detail.

The user is free to apply any digital waveform up to 80MHz during frame acquisition as external MODCLK signal. Even more, he is also free to use modulations like pseudo-random edge jitter, dithering, etc.

The signal from the MODCLK pin is used instead of the clock generated by the CGU if bit 6 in register 0x80 is set to 1. The effective modulation signal is the MODCLK divided by 4.

The unambiguity range and the integration time are in this case based on the MODCLK:

$$\text{[1]} \qquad t_{\text{INT}} \, = \, \frac{\text{reg}(\text{0x85}) + 1}{\text{MODCLK}} \cdot \left[\text{reg}(\text{0xA2:0xA3}) + 1\right] \cdot \text{reg}(\text{0xA0:0xA1})$$

For more details refer to chapter 9.2.1 and 11.3. Note, register 0x85 is active in this mode.

### 5.6. Supply, reset and start-up options

### 5.6.1. Supply voltages and external reset

During power-up, VDD and VDDPLL supplies (Figure 19) must be applied at the same time to the epc635. VDDIO can be applied either at the same time or after VDD and VDDPLL supplies become stable. In a system where VDDIO voltage is connected in parallel to application CPU IO supply pins (see Figure 15), VDD and VDDPLL can be generated by a linear regulator directly from VDDIO supply. In this case, all these three supplies ramp together.

VDDA and VDDPXH supplies must be applied as a second group, after all VDD, VDDPLL and VDDIO supplies become stable.

The negative supply VBS must be applied after all positive supplies reached their rated levels.

Image acquisition shall not start before all supply voltage are at their stable level.

RESET must be kept low while all positive voltages are ramping-up in order to guarantee proper reset of all internal circuits. As soon as rated positive levels are reached, RESET can be set to high. In case of an external clock is applied at XTALIN\_CLKIN instead of a crystal/resonator is used with on-chip OSC, clock must be present before RESET is released.

### IMPORTANT:

- It is possible to shutdown entire supplies for a very low standby current. In that case, first RESET must be driven low, then supplies must be turned off in the reverse order. Refer for details to chapter 11.5.
- VDDA and VDDPXH supplies must never kept on while turning off VDD, VDDPLL and VDDIO. Damage to the chip can be the result.

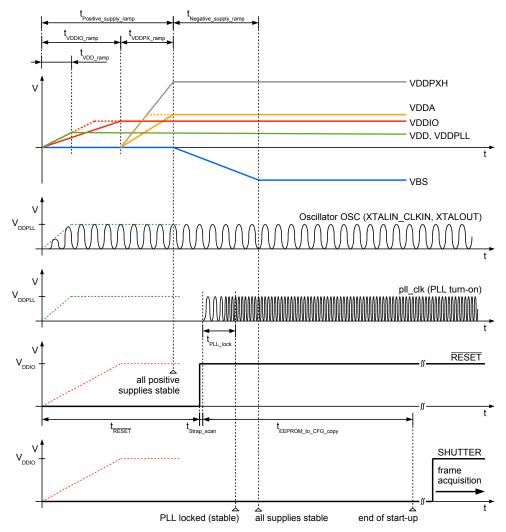


Figure 19: Power-up and reset sequence

### 5.6.2. Start-up (Clock, PLL turn-on and EEPROM copy)

The epc635 starts using either the internal 4MHz oscillator OSC with a crystal/resonator (Figure 15) or an external 4MHz clock, followed by an EEPROM copy sequence in parallel to the PLL turn-on phase. This is the factory default configuration. Several configuration registers are modified by copying the EEPROM content (Figure 51, i.e. overwrite reset values). The EEPROM copy step takes 340µs after the RESET is released.

#### 5.6.3. Strap pins

The epc635 has output pins with dual/alternative functionality for PCB level flexible start-up configuration changing, called 'strap pins'. RESET release is followed by a strap pin scanning step. The chip programs its strap pins as inputs with internal pull-down resistors enabled for 4 osc\_clk periods (refer to Table 1 and Table 3). If there is no external pull-up resistor connected, the corresponding strap pin will be scanned as logic 0 due to the internal pull-down resistor. If there is an external pull-up resistor connected (Figure 15), it will override the internal pull-down and corresponding pin will be scanned as logic 1. After the strap scan period, pins are programmed back as outputs so that they can be used for their main function. Strap pins and their definitions are listed below (Table 12).

Pin	Pin no.	Definition
HSYNC_A1	35	Set A1 bit of 7-bit I2C slave device address (section 13.1.).
VSYNC_A0	34	Set A0 bit of 7-bit I <sup>2</sup> C slave device address (section 13.1.).
XSYNC, DATA0	3, 4	Factory used strap pins. No pull-up resistors allowed

Table 12: Strap pin definition

### 5.7. LED driver

The LED driver register 0x90 is used for setting polarity etc. depending on the external LED/LD circuitry used in the application. These bit fields must not be modified during frame acquisition.

**IMPORTANT:** There are non-modulating DC modes (e.g. grayscale with LED/LD illumination) which keeps the LED driver always turned on. In this case, the user has to take care that LED driver and the epc635 chip does not exceed the maximum operating limits.

#### 5.8. DLL (Delay Line)

The modulation signal can intentionally be delayed in order to add a phase shift between the modulation of the light source and the demodulation of the backscattered light, refer to Figure 20.

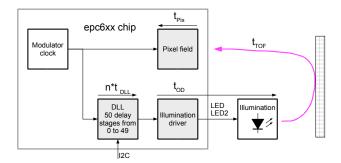


Figure 20: Block diagram of the DLL function

The purpose to do so can be that the phase shift between the modulated and the demodulated signal in a specific distance range should be at a certain value. For example, the highest distance accuracy with lowest distance noise can be achieved when the phase angle of demodulation is 45°. This is the case when all four DCS amplitudes have the same or a similar value. The worst situation is if one DCS pair is at its maximal amplitude whereas the other DCS pair is around zero (refer to Figure 21).

The DLL can be enabled in register 0xAE whereas the delay of the LED modulation can be set in steps t<sub>DLL</sub> by register 0x73 (approx. 2ns/step). The exact step t<sub>DLL</sub> by can be calculated with the value and the formula listed in register 0xE9. This value is varying from chip to chip and is also temperature dependent. The user shall characterize the overall temperature drift of the complete camera for matching the compensation.

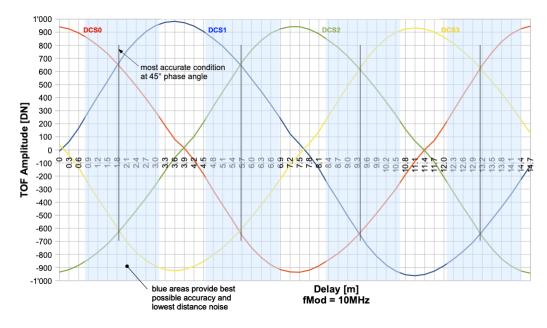


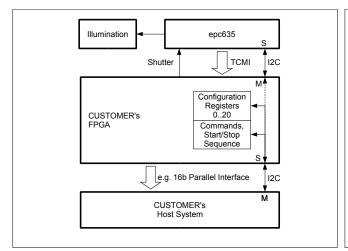
Figure 21: DCS amplitudes for the 4 DCSx (measurement data)

### Example for 10MHz modulation frequency:

If we want to optimize the accuracy of our TOF camera in the short range domain, e.g. 0m to 1m, the situation shown in Figure 21 is not ideal at all. The modulation frequency of the data shown in Figure 21 is 10MHz whereas 50 DLL Steps of approx. 2ns are equivalent to 15m distance. Shown in the diagram, the worst condition is in the first three DLL steps, which is equal to 0m to 0.9m. From then on, the distance accuracy becomes much better until DLL step 12. In other words, the distance accuracy from distance 0.9m to 3.0m is very good, but not from 0m to 0.9m. In order to be in an accurate distance measurement regime, the DLL should be shifted by 3 steps which means that the LED is delayed by 6ns.

### 5.9. Application system overview

Figure 22 and Figure 23 show a typical application block and data flow diagram. The epc635 chip acquires image data, controlled via the I2C interface, and then submits the data via the TCMI to an FPGA or microcontroller. The FPGA or microcontroller calculates the distance from the DCS' and does filtering, correction and compensation and provides a cleaned "point cloud" to the host system.



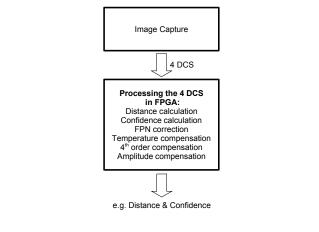


Figure 22: Block diagram

Figure 23: Data flow

# 6. TOF camera interface (TCMI)

The TOF Camera Module Interface (TCMI) is a programmable high-speed parallel data output interface to down-load the pixel data. It can be programmed very flexible via the registers 0x89, 0xCB and 0xCC.

When the integration period is completed and ADC conversion is finished, the readout results are moved into the data out buffers to be immediately transmitted via the TCMI interface. Depending of the mode selection (4x DCS, 2x DCS, ...) a programmable number of DCS frames are generated. The data is streamed out as a complete block of 1 DCS frame, one after the other. Each row contains 12-bit DCS values and the SAT bit. The pixel values are streamed out as 12 bit signed numbers. The rows are streamed out in sequence from the bottom to the top e.g. R65 (C4, C5, ... C163), R64 (C4, C5, ... C163) and so on until R6 (C4, C5, ... C163). The stream-out of one row takes 16µs with default clock settings (40MHz TCMI clock rate).

The transfer of a DCS frame cannot be interrupted or stopped, once it is started. The application should have enough bandwidth to receive all transmitted frames.

The TCMI supports two clock modes: Continuous clock (default) and gated clock, refer to chapter 6.1.1. and 6.1.2.

**IMPORTANT:** Refer to register 0xCC for setting correct data format.

The application software must take care about negative (-) single ended sample value, accordingly.

#### 6.1. TCMI clock

The DCLK frequency which is the clock for the TCMI interface is programmable to 10, 20, 40, 80MHz via register 0x89.

### 6.1.1. Continuous clock mode

This mode is selected by disabling bit 3 in register 0xCB. The frames are transmitted at high-speed using all \*SYNC (VSYNC\_A0, HSYNC\_A1, XSYNC\_SAT), DATA[7:0] and DCLK outputs (Figure 24).

All \*SYNC\*, DATA[7:0] signals are synchronously updated with the positive edge of the DCLK signal when its polarity is set as active-high; with the negative edge of the DCLK signal when its polarity is set as active-low. The non-active edge of the DCLK output can be used by the receiving end (application CPU) as a sampling clock. It should approximately be in the center of the data (refer to Figure 27).

By using the default configuration, the active states of VSYNC\_A0 and HSYNC\_A1 signals indicate blanking periods during the frame transmission. While DCLK toggles continuously, any data during the blanking periods are not valid and must be ignored.

As soon as the measurement result of the first row of the new frame is available, VSYNC\_A0 and HSYNC\_A1 are set consecutively with the next active edge of DCLK. VSYNC\_A0 is active from the start until the end of the each complete frame. Whereas, HSYNC\_A1 indicates the validity of the DATA[7:0] and XSYNC\_SAT (saturation bit) from the start until the end of a row.

By default, the XSYNC\_SAT pin is used for the saturation bit. Optionally, it can be programmed to indicate the end of a frame by disabling bit 6 in register 0xCC.

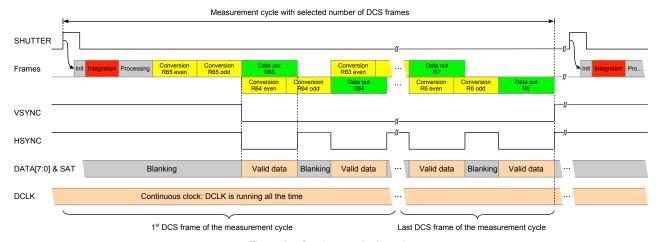


Figure 24: Continuous clock mode

#### 6.1.2. Gated clock mode

This mode is selected by enabling bit 3 in register 0xCB. The frames are transmitted at high-speed using only the DATA and DCLK outputs (Figure 25). This allows the interfacing to embedded processors with standard parallel GPIOs. The external application must take care of the begin/end of the frame/row.

DCLK signal is generated only during valid data periods. The DCLK toggle duration can be programmed to run few more cycles than HSYNC\_A1 is active effectively. This allows the external processor to finish its last operations with its FIFO/DMA.

All \*SYNC\* signals do not toggle in this mode, but can be optionally enabled.

All \*SYNC\* (optional), DATA[7:0] signals are synchronously updated with the positive edge of the DCLK signal when its polarity is set as active-high; with the negative edge of the DCLK signal when its polarity is set as active-low. The non-active edge of the DCLK output can be used by the receiving end (application CPU) as a sampling clock. It should approximately be in the center of the data.

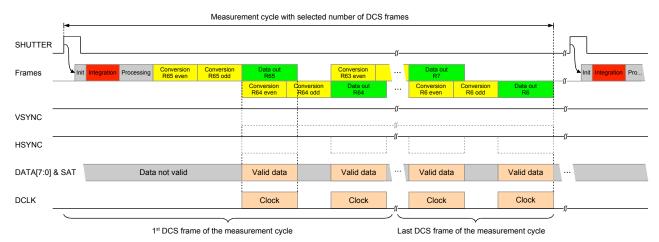


Figure 25: Gated clock mode

### 6.2. Single or continuous measurement control

### 6.2.1. Single measurement control

The selected measurement mode (4x DCS, 2x DCS, grayscale, ...) defines, how many frames the chip performs by the stimulation of one SHUTTER pulse for a measurement cycle. This pulse can be applied either by the HW SHUTTER pin or by SW control with bit 0 in register 0xA4. Whereas the SW controlled SHUTTER is auto-cleared after propagation, the HW Shutter needs a minimum hold time of 250ns and must be set back manually latest before the HSYNC\_A1 signal of the last row pair of the last DCS frame (last HSYNC\_A1 of the last frame). During such a measurement cycle, the next frame acquisition starts immediately after the last data readout on the TCMI interface until all frames are performed.

### 6.2.2. Continuous measurement control (auto-run)

As long as in the shutter control register 0xA4 bit 1 is set or the HW SHUTTER is applied during the readout of the last row pair of the last frame, the epc635 runs in a non-stop measurement mode. The chip starts immediately next measurement cycle if the actual one is terminated (Figure 29). Trigger signals not active during the readout of the last row pair of the last frame are ignored.

### 6.3. TCMI timing

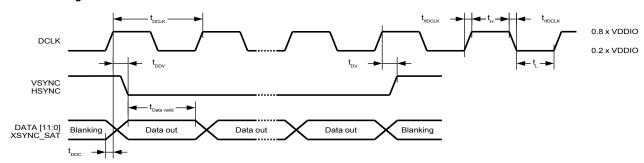


Figure 26: Detailed TCMI timing

Symbol	Parameter	Min.	Тур.	Max.	Units
t <sub>DCLK</sub>	TCMI readout clock: typ. f <sub>DCLK</sub> = 20MHz / max. f <sub>DCLK</sub> = 80MHz <sup>1</sup>		50	12.5	ns
t <sub>DDV</sub>	Delay time after positive edge of DCLK until data are valid			2.0	ns
t <sub>DDC</sub>	Data start changing before positive edge of DCLK			1.7	ns
trfDCLK	Rise and fall time of DCLK, VSYNC, HSYNC, XSYNC, Data[11:0]			2.0	ns
t <sub>H</sub>	High period of DCLK <sup>1</sup>	5.0			ns
t <sub>L</sub>	Low period of DCLK <sup>1</sup>	3.5			ns
t <sub>Data valid</sub>	Output data on the TCMI interface are valid (depends on DCLK)	8.8			ns

Table 13: TCMI timing parameters ( $C_L = 20 pF max.$ )

Note 1: Is DCLK > 40MHz, t<sub>H</sub> and t<sub>L</sub> value need to be reduced by 2.5ns for covering safely delay and jitter effects of this output.

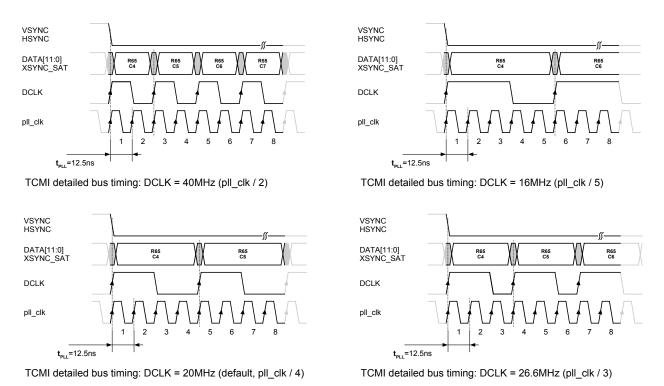


Figure 27: TCMI timing examples with symmetric and asymmetric DCLK

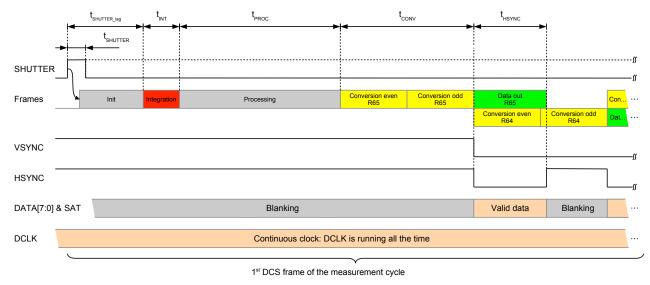


Figure 28: Frame timing: Start 1st DCS frame (DCLK: 20MHz)

#### Note:

To avoid readout rollover when using slower DCLK e.g. DCLK < 5MHz, bit 6 in register 0x91 must be set (refer to chapter 14.2.). It stretches HSYNC for slower TCMI interfaces. It causes a reduced DCS frame rate due to additional  $2\mu s$  per ADC conversion ( $t_{conv}/2 + 2\mu s$ ).

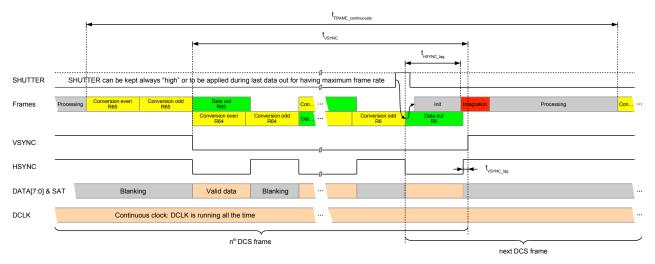


Figure 29: Frame timing: Inter frame timing, end of frame and start next frame (DCLK: 20MHz)

### 6.4. TCMI data format

TCMI supports three 8 bit transfer formats:

■ msb/lsb split mode: Transfers 12 bit pixel data with MSByte leading and LSByte trailing with 2x DCLK.

Refer to Table 14 and Figure 30.

■ Isb/msb split mode: Transfers 12 bit pixel data with LSByte leading and MSByte trailing with 2x DCLK.

Refer to Table 15 and Figure 31.

■ 8-bit mode: Transfers the 8 MSB bits of the pixel data with 1x DCLK.

Refer to Table 16 and Figure 32.

The three modes require lines DATA[7:0] to be connected in the application. The TCMI data format can be selected in the register 0xCB. The two split modes transmit pixel values in two consecutive DCLK cycles. As a result, HSYNC time is doubled. When 8 bit precision is enough, the application can use 8-bit mode.

			1st Byte:	MSByte	!			2nd Byte: LSByte							
D7	D6	D5	D4	D3	D2	D1	D0	D7 D6 D5 D4 D3 D2 D1					D0		
b11	b10	b9	b8	b7	b6	b5	b4	b3	b2	b1	b0	0	0	0	SAT

Table 14: TCMI msb/lsb split mode, HW synchronization data format

			1st Byte	: LSByte				2nd Byte: MSByte							
D7	D6	D5	D4	D3	D2	D1	D0	D7 D6 D5 D4 D3 D2 D1					D0		
b3	b2	b1	b0	0	0	0	SAT	b11	b10	b9	b8	b7	b6	b5	b4

Table 15: TCMI lsb/msb split mode, HW synchronization data format

	Byte												
D7 D6 D5 D4 D3 D2 D1 D0													
b11	b10	b9	b8	b7	b6	b5	b4						

Table 16: TCMI 8-bit mode, HW synchronization data format

TCMI data formats can be combined with the ADC conversion speed up. Refer to chapter 7 for ADC resolution v.s. conversion time setting.

The saturation flag can be optionally inserted into the DATA[0] of the LSByte by setting bit 6 in register 0xCB during the first or second DCLK cycle for the msb/lsb or lsb/msb split modes, respectively. This feature is not available for the 8-bit mode. In this case either the XSYNC\_SAT pin can be used along with the DATA[\*] pins or bit 7 in register 0xCC must be set to force all DATA[\*] = 0xFFF when the corresponding pixel is saturated.

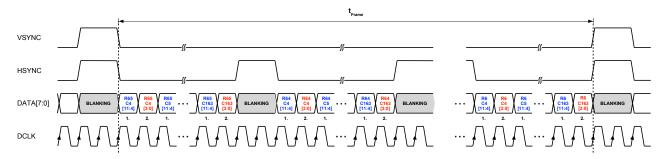


Figure 30: msb/lsb split mode

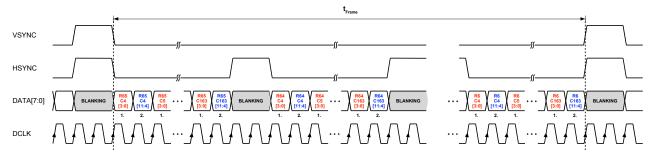


Figure 31: Isb/msb split mode

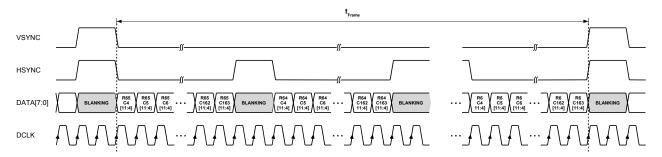


Figure 32: 8-bit mode

### 6.5. TCMI embedded synchronization mode

Embedded Synchronization Mode ESM uses only DCLK and DATA[\*] to transmit the whole image. It eliminates using hardware VSYNC, HSYNC, XSYNC for synchronization. By setting bit 2 in register 0xCB, ESM embeds data packets so called "Labels", before and after every frame and row to mark begin and end of the valid pixel samples on the TCMI data bus. The synchronization labels consist of 4 consecutive bytes, starting always with 0xFF, followed by 0x00, ending with a unique byte as defined designator as given in Table 17.

Label	4-Byte Data Packet	Description			
FS	0xFF 00 00 1E	Frame Start			
FE	0xFF 00 00 E1	Frame End			
LS	0xFF 00 00 AA	Line Start			
LE	0xFF 00 00 <b>55</b>	Line End			

Table 17: TCMI ESM labels

The receiver/application continuously parses the incoming data for ESM labels and strips out the image data marked between LS-LE pairs. Figure 33 illustrates an example of a DCS frame transfer. Label ending bytes can be customized by changing the values in the registers 0x1C, 0x1D, 0x1E and 0x1F.

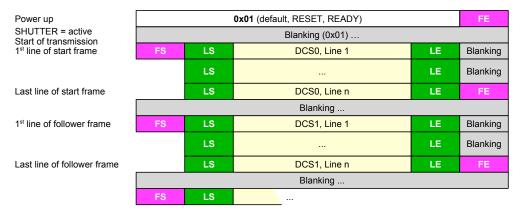


Figure 33: TCMI ESM frames

Values 0x00 and 0xFF will not occur in the image data due to the use of the labels. Therefore, image data is mapped to values between 0x01 ... 0xFE. Is the TCMI bus idle (i.e. blanking), TCMI keeps DATA[7:0] = 0x01 (default value of the bus after reset).

ESM data mapping details for different TCMI data formats are defined in Table 18, Table 19 and Table 20:

D0 ... D7 DATA0, DATA1, ... DATA7 lines of the TCMI bus.

b0 ... b11 pixel value

SAT, SAT saturation information

		,	1st Byte:	MSByte	•			2nd Byte: LSByte							
D7	D6	D5	D4	D3	D2	D1	D0	D7 D6 D5 D4 D3 D2 D1					D0		
0	1	b11	b10	b9	b8	b7	b6	b5	b4	b3	b2	b1	b0	SAT	SAT

Table 18: TCMI msb/lsb split mode ESM data mapping

			1st Byte	: LSByte	•			2nd Byte: MSByte							
D7	D6	D5	D4	D3	D2	D1	D0	D7 D6 D5 D4 D3 D2 D1					D1	D0	
b5	b4	b3	b2	b1	b0	SAT	SAT	0	1	b11	b10	b9	b8	b7	b6

Table 19: TCMI Isb/msb split mode ESM data mapping

	Byte												
D7	D7 D6 D5 D4 D3 D2 D1 D0												
b7	b6	b5	b4	b3	b2	b1	b0						

Table 20: TCMI 8-bit mode ESM data mapping

### 6.6. Frame rate and data-out performance

The epc635 can perform a maximum of 512fps with 1 $\mu$ s integration time, 40MHz modulation clock, 20MHz DCLK, 1x DCS and continuous measurement control. For 3D TOF, each frame is referred as a DCS frame. Either 4x (with  $\pi$ -delay matching) or 2x (without  $\pi$ -delay matching) DCS frames must be acquired for one distance calculation. Therefore, the resulting distance measurement rate turns out to be 128 fps or 256 fps respectively. For the grayscale mode the maximum frame rate of 512 fps is possible.

Symbol	Parameter	Min.	12 bit	8 bit	Units
t <sub>DCLK</sub>	TCMI readout clock e.g. f <sub>DCLK</sub> = 20MHz		50		
t <sub>SHUTTER</sub>	Hold time for the signal on pin SHUTTER	250			ns
t <sub>SHUTTER_lag</sub>	Delay from the rising edge of SHUTTER signal to the 1st LED pulse		18		
t <sub>INT</sub>	Image acquisition (integration time)		1		
t <sub>PROC</sub>	Delay from the last LED pulse until the 1st row conversion		39.25		
t <sub>CONV</sub>	Conversion time for one row		31.5	24.5	μs
t <sub>HSYNC</sub>	Readout time for a row e.g. f <sub>DCLK</sub> = 20MHz		16	8	μs
t <sub>HSYNC_lag</sub>	Delay from the begin of last readout until the 1st LED pulse of next DCS frame		17		μs
t <sub>VSYNC_lag</sub>	Delay end of HSYNC to end of VSYNC at the end of each DCS frame		5	ns	
tvsync	Data readout time for one DCS frame e.g. $f_{DCLK}$ = 20MHz $t_{VSYNC}$ = ( $t_{CONV}$ x 59 rows) + $t_{HSYNC}$ + $t_{VSYNC\_lag}$		1.874	1.454	ms
	Single measurement control mode:				
t <sub>1st_FRAME_START</sub>	Delay from rising edge of SHUTTER signal until start of data readout of 1st frame		89.75	82.75	μs
t <sub>1st_FRAME_TOTAL</sub>	Total time for reading one DCS or grayscale frame from rising edge of SHUTTER signal until end of readout of 1st frame		1.964	1.536	ms
	Continuous measurement control mode:				
t <sub>FRAME_continuously</sub>	Total time for reading one DCS or grayscale frame term term term term term term term te		1.527	ms	
t <sub>4DCS_continuously</sub>	Total time for one 3D TOF distance measurement (4 DCS) $t_{\text{FRAME\_continuously}} = ((t_{\text{CONV}} \times 60 \text{ rows}) + t_{\text{HSYNC\_lag}} + t_{\text{INT}} + t_{\text{PROC}}) \times 4 \text{ DCS}$			6.108	ms

Table 21: Timings for one DCS or grayscale frames and for 3D TOF distance measurements (4x DCS) (Reference: see Figure 28 and Figure 29, f<sub>DCLK</sub> = 20MHz, t<sub>INT</sub> = 1μs)

### 6.7. Memory space estimation

Every frame (DCS) generates up to  $160 \times 60$  pixel x 13 bit (Data + SAT) = 125 kBit. Stuffed to 16 bit words, the memory needed to store one DCS frame is 19.2kByte. Depending on the operation mode, up to 10 full frames or even more are needed. Thus, the minimum image memory RAM should be 256kByte.

### 7. Pixel architecture

The pixels are placed in groups 2x2 pixels, called herein "pixel group". The pixel group performs two basic operations: Measurement (integration) and readout (ADC). Pixels are named as UE (Upper-row, Even-column), UO (Upper-row, Odd-column), LE (Lower-row, Even-column) and LO (Lower-row, Odd-column) depending on their location within the pixel group (see Figure 34). Pixels with the same name are controlled simultaneously in the whole pixel-field. More precisely, pixels in the upper and lower rows are controlled simultaneously during measurement, pixels in the even and odd columns are controlled simultaneously during readout.

The pixel group architecture allows the epc635 to operate the pixel-field in different modes and in combinations thereof according the following chapters.

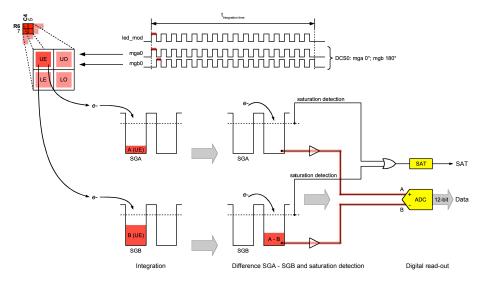


Figure 34: The 2x2 pixel group and the simplified function overview

Each pixel of the pixel group has its own pair of storage gates SGA and SGB. During the integration time, they accumulate the charges (e-) created by the reflected modulated light coming from the object (see section 9., Imaging). They are controlled by the mga and mgb demodulation signals. After the measurement is finished, the readout phase starts. The charges stored in the storage gates SGA and SGB are read out as a difference A – B (ambient-light suppression) and converted into a single 12-bit digital value and a 1 bit saturation flag. The output value can be either positive or negative depending on the demodulated phase and the offset of the signal chain.

# 8. Pixel-field and operation modes

#### 8.1. Pixel coordinates

The epc635 pixel-field consists of a total of 168 x 72 pixels whereas 160 x 60 are active. 4 rows top/bottom and 6 columns left/right on the periphery of the pixel-field contain dummy pixels. The upper-left corner (top view on chip) is the origin (4/6) of the epc635 pixel-field. X-axis starts at 4 and counts up to 163 to the right. Pixel y-axis starts at 6 and counts up to 65 to the bottom. All readout modes and control registers use this coordinate system to set or change modes of the chip.

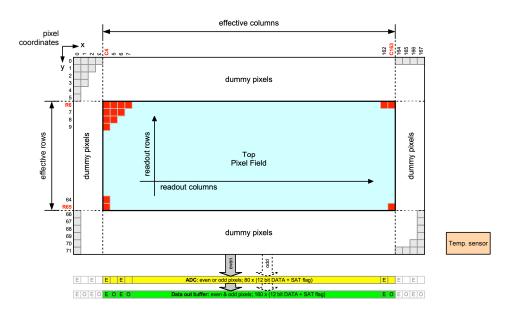


Figure 35: Pixel-field coordinates with row and column numbering scheme (top-view, solder balls are bottom side)

Readout starts at the bottom of the pixel-field and continues towards up, row by row. Thus the higher the row number the more dark current is collected by the pixels which appears like an increased DC offset of the pixel value (refer to 1.4.). The internal readout of a row is split in two sections: first all even pixels; second all odd pixels. Later on the TCMI interface presents the row in the regular order with even and odd pixels mixed.

### 8.2. Operation modes

#### 8.2.1. Full resolution mode (default)

This is the default operation mode for 3D TOF operation. All UE, UO, LE, LO storage gates work simultaneously during measurement operation. The storage gate control signals mga, mgb are applied to all pixels simultaneously (see Figure 36). One, two or four DCS can be acquired in this mode.

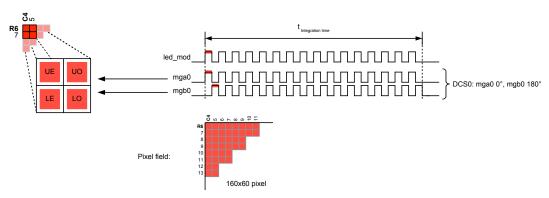


Figure 36: Full resolution mode: even and odd pixel rows are controlled identically with mgx0

#### 8.2.2. Dual phase mode (motion blur reduction)

In this mode, the odd an the even rows are controlled by 90° phase shifted signals (see Figure 37). This mode allows to acquire two 90° shifted DCSs at the same time, e.g. DCS0 and DCS1. In the two-DCS mode, distance calculation can be accomplished within one acquisition. Thus, motion blur is eliminated. The even row pixels store DCS0 (or DCS2) while the odd row pixels store DCS1 (or DCS3). The vertical pixel pairs (e.g. UE/LE) must be treated for distance calculation as if they are one single pixel. This comes at the cost of a reduced resolution along the y-axis. The result provides a total of 160x60 pixel-field readout with an effective 3D TOF resolution of 160x30 pixel. Select this mode according chapter 11.4.1.

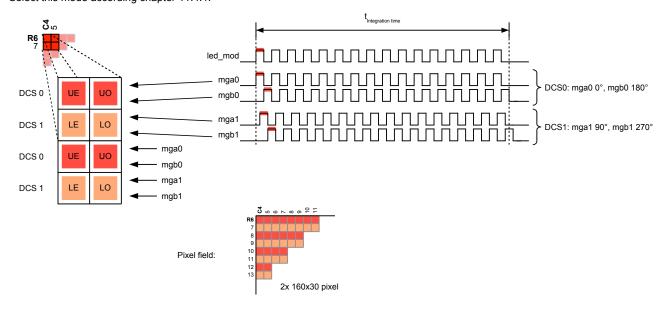


Figure 37: Dual phase mode with phase-shifted integration time even and odd rows independently controlled by mgx0 and mgx1 with different phase shifts

### **IMPORTANT:**

This mode requires that adjacent pixels look to the same point on the target and receive the same amount of light. Otherwise, calculated distance values are not reliable.

Pixel with a big offset or defective pixel will lead to completely wrong distance values with its paired pixel. Thus, the pixel group has to be discarded.

### 8.2.3. Dual integration time mode (high dynamic range, HDR mode)

In this mode, the odd an the even rows are controlled by different integration time lengths. This mode allows to acquire one image with two different integration time in oder to increase the dynamic range. Both groups provide exactly the same DCS modulation signals (phases). One stops earlier than the other due to different integration times (see Figure 38). As a consequence, the two pixels collect different amount of light simultaneously. There is no restriction about which integration time is shorter or longer with respect to the other. The even row pixels integrate with integration length 1, register 0xA2 and 0xA3 while the odd row pixels integrate with integration length 2, register 0x9E and 0x9F. The even and odd pixels (e.g. UE, LE) can be used independently for distance calculation. This comes at the cost of a reduced resolution along the y-axis. Instead of one frame with 160x60 pixels, a single readout provides two DCS or black and white frames with an effective resolution of 160x30 pixels but with different integration times.

Select this mode according chapter 11.4.2.

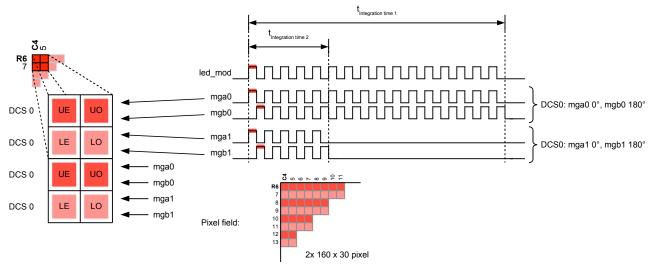


Figure 38: Dual integration time mode: even and odd rows independently controlled by mgx0 and mgx1. One stops earlier than the other

#### 8.3. Pixel saturation detection

The pixels collect continuously modulated and non-modulated ambient light during the integration period. Depending on these light intensities, sometimes the pixels collect more charge (over-exposure) than they can accommodate in their storage gates (refer to Figure 34). In such a case, the 12 bit sample data is not valid and cannot be used for distance calculation.

#### 8.3.1. Hardware saturation flag

Each pixel generates a "saturation detection" flag along with the sample data, so that the data can be discarded by the application. The saturation flag is transmitted via XSYNC\_SAT pin with every pixel.

#### 8.3.2. Software saturation flag

If XSYNC\_SATpin is used for an another function by setting register 0xCC, bit 6, bit 7 in register 0xCC enables to drive all DATA[11:0] to 0xFFF when the pixel is saturated.

#### 8.4. ADC conversion speed-up

Applications which need e.g. only 8-bit resolution e.g. grayscale mode, the frame rate can be increased further by reducing the resolution of the ADC conversion. This mode can be combined with the 8-bit TCMI data format by setting bit 4 and 5 in register 0xCB to 11.

Register		ADC Resolution		
Name	Address	8-bit	12-bit	
ADC control	0xCD	0x1B	0x13	
ADC resolution control	0x9D	0x34	0x50	
Conversion time per row		24.5 µs	31.5µs	

Table 22: ADC resolution setting

## 9. Imaging

### 9.1. Distance measurement (3D TOF)

The epc635's default modulation mode is based on the sinusoidal TOF modulation theory but uses effectively for the illumination a square-wave modulated signal with a duty cycle of 50%. After reset, all internal register values are default to operate the chip at 4MHz XTAL/external clock input, multiplied up to 40MHz at the PLL output, clocks the modulator with 40MHz modulation clock (mod\_clk), modulates LED/LD with 10MHz and acquires 4 successive DCS frames (0 ... 3) using 51.2µs integration time.

The distance measurement mode uses the on chip LED driver and the external LED/LD to provide modulated light on the target. Modulation control signals to the LED driver are provided by a programmable modulator. The modulator generates all signals to modulate the external LED/LD and simultaneously all demodulation signals to the pixel-field. TOF and grayscale mode with all the variants are generated here.

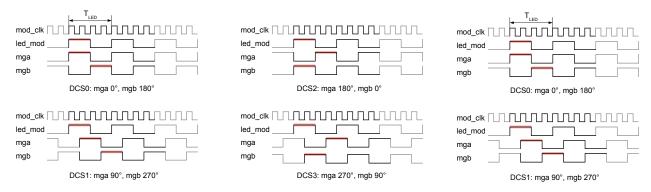


Figure 39: 4 DCSx modulation/demodulation waveforms

Figure 40: 2 DCSx mod./demod. waveforms

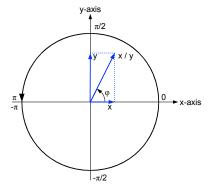
The modulation table registers 0x22 ... 0x2D control the modulation (refer to Table 35). The registers can be updated via I<sup>2</sup>C bus between frame acquisitions. The application must take care that the last frame's integration phase is completed before modifying these registers on the fly. This time can be detected by the application by waiting for the falling-edge of VSYNC or the first falling-edge of HSYNC signal after shutter pulse/command was applied. This allows to run continuously at the maximum frame rate. For a full-frame readout, the margin is a 3.6ms to alter these registers via I<sup>2</sup>C on the fly.

With the application of the shutter pulse (HW SHUTTER or SW shutter via I<sup>2</sup>C), the chip performs the required number of successive DCS acquisitions. Each one of the 4 DCS frame types has a different phase relation between modulation (led\_mod) and demodulation (mga, mgb) signals which makes phase-to-distance calculation possible. In case of DCS0, led\_mod is phase-shifted by 0° and 180° with respect to mga and mgb, respectively. In case of DCS1, led\_mod is phase-shifted by 90° and 270°. For DCS2, the phase shifts are 180° and 0° and for DCS3, the phase shifts are 270° and 90° (see Figure 39). Note that for DCS2 and DCS3, the demodulation signals mga and mgb are simply swapped with respect to DCS0 and DCS1, respectively.

By programming the number of DCS readouts = 01 (see 0x92 register), shutter initiates 2 successive DCS frame acquisitions (see Figure 40). This mode allows distance acquisition by using two DCSs only and thus a doubled frame rate. However, the cost is a lower distance measurement accuracy and a 40% higher distance noise.

#### 9.2. Distance calculation algorithm

The use of the trigonometric atan2 definition for vectors (x, y) in the Cartesian coordinate system  $\varphi = \text{atan2}(x, y) = \text{atan2}(y/x)$  guarantees a continuous distance calculation algorithm in the range of phases between  $-\pi \dots +\pi$ . In our case, we use the range from  $0^{\circ} \dots 360^{\circ}$  which corresponds to the distance from 0m up to the unambiguity distance (refer to Figure 41 and Figure 42).



amplitude

timo

timo

time

Figure 41: Continuous atan2 representation for the range  $-\pi$  ...  $+\pi$ 

Figure 42: Sampling of the received waveform

Typically, the distance is calculated by using the 4 DCSs, also called  $\pi$ -delay matching which cancels pixels offsets leading to distance errors:

$$[2] \quad \mathsf{D}_{\mathsf{TOF}}\left[\mathsf{m}\right] \,=\, \frac{\mathsf{c}}{2} \cdot \frac{1}{2 \, \pi \, \mathsf{f}_{\mathsf{LED}}} \cdot \left[ \pi + \mathsf{atan2} \bigg( \frac{\mathsf{DCS3} - \mathsf{DCS1}}{\mathsf{DCS2} - \mathsf{DCS0}} \bigg) \right] + \mathsf{D}_{\mathsf{OFFSET}}$$

The measured data are always over the  $360^{\circ}$  phase-shift valid. Due to the distance offset adjustment D<sub>OFFSET</sub>, the correction of the distance roll-over effect at zero and unambiguity distance is necessary for having all the time correct distance values D:

■ if  $D_{TOF} > D_{Unambiguity}$ :  $D = D_{TOF} - D_{Unambiguity}$ ■ if  $D_{TOF} < 0$ :  $D = D_{TOF} + D_{Unambiguity}$ 

 $\blacksquare$  else:  $D = D_{TOF}$ 

If higher distance errors can be tolerated but a high frame rate is needed, the distance calculation also works with 2 DCSs only:

$$[3] \quad \ D_{\text{TOF}}\left[m\right] \ = \ \frac{c}{2} \cdot \frac{1}{2\pi f_{\text{LED}}} \cdot \left[\pi + \text{atan2} \left(\frac{-\text{DCS1}}{-\text{DCS0}}\right)\right]$$

The following terms are used in the formulas above:

 $D_{\text{TOF}} \hspace{1cm} \text{Distance in meters [m]} \\$ 

c Speed of light (299,792,458 m/s)

f<sub>LED</sub> LED/LD modulation frequency e.g. 10MHz

DCS0 - DCS3 Sampling values [LSB]

φ Phase shift caused by the time-of-flight [rad]

 $\begin{array}{ll} D_{\text{OFFSET}} & \text{Offset compensation [m]} \\ D_{\text{Unambiguity}} & \text{Unambiguity distance [m]} \end{array}$ 

### 9.2.1. Unambiguity range versus time base setting

Due to continuous modulation, roll-over can be observed if the distance to the object is longer than the length of one modulation cycle (one period, 2π). This roll-over distance is called unambiguity range can be calculated as follows:

$$\text{[4]} \quad D_{\text{Unambiguity}}\left[m\right] \, = \, \frac{c}{2} \cdot \frac{1}{f_{\text{LED}}}$$

The operating range is the maximum distance which corresponds to the maximum time-of-flight inside of one period of the used modulation: it is one period of f<sub>LED</sub>. Objects inside this area are detected unambiguously.

The unambiguity range defines the repetition distance, where objects outside of the targeted operating range can still be detected as far they are of very high reflectivity (remission). Strongly reflected signals outside of this range may therefore interfere with the measurement.

The operating range, the unambiguity distance, the time base for the integration time and the resolution of the distance signal are defined by the modulation clock mod\_clk. This corresponds for the epc635 to a maximum default operating range of 7.5m @ mod\_clk = 80MHz. It may be necessary depending on the application to adapt these parameters to other values. It can be done by a change of the modulation clock. Table 23 lists as an example some values of the modulation clocks in function of the operating ranges, the unambiguity distances, of the distance resolutions and of the multipliers of the integration time base.

Unambiguity distance	Integration time		Modulation clock	Modulation clock divider	LED modulation frequency	
	multiplied by	resolution <sup>2</sup>	f <sub>MOD</sub>	Register 0x85	f <sub>LED</sub>	
[m]	[#]	[cm]	[MHz]	[#]	[MHz]	
7.5	1	0.25	80	0	20	
15 ¹	2 1	0.50	40	1 ¹	10	
30	4	1.00	20	3	5	
60	8	2.00	10	7	2.5	
120	16	4.00	5	15	1.25	

Table 23: Unambiguity range versus on-chip modulation clock

#### Notes:

- <sup>1</sup> Default values
- <sup>2</sup> The distance resolution is given for an operating range corresponding to 3'000 LSB.
- <sup>3</sup> Using external modulation clock MODCLK: Follow chapter 5.5.

### 9.2.2. Quality of the measurement

The DCS values contain not only the distance information, but also the quality and the validity (confidence level) of the received optical signal. The higher the signal amplitude of the received signal, the better and more precise the distance measurement. Each distance measurement of every pixel has its own validity and quality.

The primary quality indicator for the measured distance data is amplitude of the received modulated light A<sub>TOF</sub>. The amplitude is in direct relationship to the distance noise (refer to Figure 5). The amplitude can be calculated as follows:

[5] 
$$A_{TOF} = \frac{\sqrt{(DCS2 - DCS0)^2 + (DCS3 - DCS1)^2}}{2}$$

Amplitude A <sub>TOF</sub>	Classification	Action
< 25 LSB	Weak illumination	Objects can be detected but distance measurement is not possible. Increase the integration time for the next measurement.
25 100 LSB	Useful for measurement	High distance noise, increase the integration time
100 2'000 LSB	Good signal strength	No action necessary
> 2'000 LSB	Overexposed	Decrease integration time for the next measurement.

Table 24: Signal amplitude versus classification

### Note:

The amplitude value is the feedback parameter that is used to set the integration time for the next measurement. Generally, the higher the received signal, the better and more precise the distance measurement. However, it is good practice to control the integration time such that an amplitude value between 200 ... 1'500 LSB is achieved. Higher values will only slow down the acquisition rate due to longer integration times, but are not significantly improving signal to noise ratio.

The quality indicator for the distance noise is the ratio of ambient-light  $E_{\text{BW}}$  to the value of modulated light  $E_{\text{TOF}}$  (AMR). This value may be calculated and used additionally to the above amplitude value if the respective application is subject to intense ambient-light. The irradiance  $E_{\text{TOF}}$  of the modulated signal at the surface of a pixel can be calculated by the AC sensitivity  $S_{\text{TOF}}$ , the used integration time  $t_{\text{INT-TOF}}$ , the reference integration time  $t_{\text{INT-REF-TOF}}$  and the amplitude  $A_{\text{TOF}}$  of the received modulated signal the following way:

$$\text{[6]} \qquad \text{E}_{\text{TOF}} \,=\, \text{S}_{\text{TOF}} \cdot \frac{t_{\text{INT-REF-TOF}}}{t_{\text{INT-TOF}}} \cdot \text{A}_{\text{TOF}} \quad \text{e.g.} \quad \text{E}_{\text{TOF}} \,=\, 0.60 \, \frac{\text{nW/mm}^2}{\text{LSB}} \cdot \frac{100 \, \mu \text{s}}{250 \, \mu \text{s}} \cdot 1'000 \, \text{LSB} \,=\, 0.24 \, \mu \, \text{W/mm}^2$$

The formula to calculate the quality indicator "Ratio of ambient-light / modulated light" (AMR) is

$$[7] \qquad \mathsf{AMR}[\mathsf{dB}] \ = \ 20 \cdot \mathsf{log} \bigg( \frac{\mathsf{E}_{\mathsf{BW}}}{\mathsf{E}_{\mathsf{TOF}}} \bigg) \qquad \qquad \mathsf{e.g.} \quad \mathsf{AMR}[\mathsf{dB}] \ = \ 20 \cdot \mathsf{log} \bigg( \frac{15.6 \mu \, \mathsf{W}/\mathsf{mm}^2}{0.24 \mu \, \mathsf{W}/\mathsf{mm}^2} \bigg) \ = \ 36 \mathsf{dB}$$

To obtain the E<sub>BW</sub> please refer to chapter 9.3. Grayscale imaging. This ratio is one of the influencing factors regarding the distance noise.

AMR value	Classification	Action
< 60 dB	excellent	No action necessary.
< 70 dB	sufficient	Is a lower noise level needed, do the next measurement with a shorter integration time or with an increased illumination power.
> 70 dB	weak	Do the next measurement with a shorter integration time or with an increased illumination power.

Table 25: Classification ratio ambient-light to modulated light (AMR) versus distance noise

There are also validity indicators delivered by the chip after a measurement. These will help to detect saturated or not illuminated pixels as a result of too much/less illumination or too long/short integration time.

Table 26 shows a quality decision matrix as a summary of the validity and quality parameters for the distance measurement.

Step	Indicator	Pixel saturation: too much amblight or too bright illu.	Too bright illumination	No object detected	Too much ambient-light	Object detected
1	SAT flag	Set				
2	DCSx		> +99% or < -99%	all of them -1% +1%		
3	TOF amplitude		> 99%	< 1%		5% 99%
4	AMR: Ratio amb. to mod. light				> 70 dB	< 60 dB
5	Action	Decrease int. time	Decrease int. time	Increase int. time	Decrease int. time	Use distance data

Table 26: Validity (V) and quality (Q) decision matrix (see also to Figure 47)

#### 9.3. Grayscale imaging

The grayscale mode allows using the epc635 as a grayscale imager. This mode can be used either without LED/LD illumination for ambient-light measurements or with LED/LD for active illumination of the scenery. The grayscale measurement uses regular DCS measurement but with DCS0 only. It is performed with differential readout using MGA only which stays on all the integration time. Data output format is signed integer 12 bit: ± 2'047 LSB. Effective data range is 0 ... +2'047. Due to system noise around zero, the readout can show small negative numbers. Corresponding registers settings can be found in 0x3A (= 0x00) and 0x3C (= 0x26). Due to the fact that distance measurement results can be influenced by ambient-light, the grayscale measurement without illumination can thereof be used as an important quality and correction parameter for the distance measurement.

The saturation flag status is invalid in this mode.

The irradiance  $E_{BW}$  of the grayscale signal at the surface of a pixel can be calculated from the DC sensitivity  $S_{BW}$ , the used integration time  $t_{INT-BEF-BW}$  and the amplitude of DCS0 of the grayscale signal as follows:

$$[8] \qquad \mathsf{E}_{\mathsf{BW}} \ = \ \mathsf{S}_{\mathsf{BW}} \cdot \frac{\mathsf{t}_{\mathsf{INT\text{-}REF\text{-}BW}}}{\mathsf{t}_{\mathsf{INT\text{-}BW}}} \cdot \mathsf{DCS0} \qquad \qquad \mathsf{e.g.} \quad \ \mathsf{E}_{\mathsf{BW}} \ = \ 0.25 \frac{\mathsf{nW/mm}^2}{\mathsf{LSB}} \cdot \frac{100 \mu \, \mathsf{s}}{1.6 \, \mu \, \mathsf{s}} \cdot 1'000 \, \mathsf{LSB} \ = \ 15.6 \, \mu \, \mathsf{W/mm}^2 \, \mathsf{s}^2 + 1'000 \, \mathsf{LSB} \ = \ 10.0 \, \mu \, \mathsf{s}^2 + 1'000 \, \mathsf{LSB} \ = \ 10.0 \,$$

### 9.4. Calibration and compensation of TOF cameras

This modern TOF sensor chip offers a fully digital interface to the control circuitry of a TOF camera. The first time user naturally expects straight forward implementation and digital accuracy of the measured signals. Unfortunately, this is often followed by tremendous disillusion because of the many physical effects influencing the final performance of 3D TOF cameras.

3D TOF cameras capture images by utilizing the time-of-flight measurement of photons. Photons are emitted by high frequency modulated LEDs or Laser Diodes, which are part of the camera, then scattered from objects in the scenery and finally, some of the emitted photons are reflected back to the camera and captured in so-called demodulation pixels. This time-of-flight happens in an incredibly short period of time as it takes place with 300,000km/s or 30cm/ns. If one would like to achieve a centimeter distance resolution and accuracy, 30ps time measurement accuracy has to be achieved. This is a very tough requirement, especially if tens of thousands of pixels shall provide such accurate measurement several dozen times per second at the same time. Small and inherent differences in the connection and arrangement of transistors within the TOF chip, temperature differences and changes, but also irradiance signal strength and last but not least ambient light change lead to measurement errors in the tens of centimeters:

Calibration and compensation is essential to reach the goal.

To support users, ESPROS issued on the Website www.espros.com in the section "Downloads" the application note AN10 "Calibration and compensation of Cameras using ESPROS TOF Chips". This paper describes the error sources in 3D TOF sensor chips, a simple way to implement a calibration procedure and how to compensate them on camera level.

Other documents which can be helpful to achieve a successful implementation of the chip are listed in chapter 16.2 Related documents.

#### 9.5. Noise reduction and signal filtering

Whatever measurement process is applied, distance noise is one of the major challenging factors of 3D TOF imaging. It limits to distinguish in depth between small objects or fine contours. It is called temporal noise and varies from measurement to measurement. Since this noise is a statistical value, its effect can be reduced by filtering.

However, a simple averaging with a FIR filter is not suitable in many applications because of the very long time lag to get a filtered result. Filtering based on the theory of Rudolf E. Kalman, noise can be reduced significantly without losing responsivity of the system. Figure 43 shows the resulting effect of such a Kalman filter.

Left side: The frames 0 to 120 have been acquired without filtering at all. The distance noise is approx. 12cmpp (1 sigma = 2.5cm). Right side: Frames 121 to 250 are processed with the Kalman filter. The distance noise is reduced to approx. 2cmpp (1 sigma = 0.5cm). The signal amplitude was quite low in both cases, approx. 250 LSB.

To support users, ESPROS issued on the Website www.espros.com in the section "Downloads" the application note AN12 "Distance Noise Reduction with Kalman Filter". This paper describes background and implementation of two Kalman filter algorithms in 3D TOF cameras.

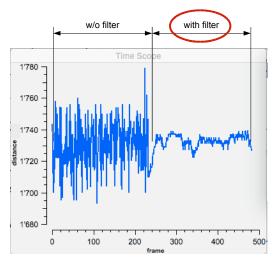


Figure 43: Effect of the static Kalman filter on distance noise (Distance in mm)

# 10. Temperature sensor

The temperature sensor is located near the pixel-field. It is factory calibrated at 27°C (offset). The temperature value can be accessed in registers 0x60 and 0x61 after taking a grayscale image. The sensitivity for taking the grayscale image with the procedure described below is 2.5 times lower compared to the regular grayscale modes described in chapter 11. Most applications need grayscale (or ambient-light) pictures for background-light compensation. By reading the temperature, a grayscale image can be read at the same time.

#### 10.1. Initialization

upon power-up or after a RESET:

```
define X, Y, M, C, Z,
                                     # Define required variables
       TH, TL, Temp
                                     # Define required variables, only for temperature reading
X = RD @0xD3
                                     # Save register 0xD3
Y = RD @0xD5
                                     # Save register 0xD5
C = RD @0xE8
                                     # Read sensor factory calibration
Z = C/4.7 - 0x12B
                                     # Normalized calibration value for temperature formula
# Set defaults for grayscale
WR @0x3C = 0x26
                                     # Ambient only (default factory setting)
WR @0x3A = 0x00
                                     # Differential readout (default factory setting)
```

The calibration value (factory setting) is stored in the EEPROM of the chip. If it is accidentally overwritten, it can be reloaded by applying a reset or a power-up.

#### 10.2. Read-out during runtime

- 1. Set the integration time for the grayscale image the regular way. Note: The sensitivity is 2.5 times lower than in the regular grayscale mode.
- 2. Acquire a grayscale image, do the temperature readout and the temperature calculation. The grayscale image will be acquired with the following procedure and stores the temperature value into the registers 0x60 and 0x61.

```
# Save mode register, control no. of DCS
M = RD @0x92
WR @0xD3 = X OR 0x60
                                     # Set bits b5 and b6
WR @0xD5 = Y AND 0x0F
                                     # Clear bits b4 and b5
# Image acquisition
WR @0x92 = 0xC4
                                     # Change mode to grayscale
WR @0xA4 = 0x01
                                     # Trigger image acquisition
                                     # (can also be done with a hardware shutter pulse)
# Wait until the image is transferred (VSYNC goes high)
TH = RD @0x60
                                     # Read temperature sensor high register
TL = RD @0x61
                                     # Read temperature sensor low register
# Switch back to normal image acquisition...
WR @0xD3 = X
                                     # Restore register 0xD3
WR @0xD5 = Y
                                     # Restore register 0xD5
WR @0x92 = M
                                     # Change back to the mode before temperature reading
```

### 10.3. Calculate temperature in °C

```
Temperature = (TH*0x0100+TL-0x2000)*0.134+Z
```

### Note:

The grayscale image which has been acquired can be used. However, the sensitivity during this acquisition was reduced by a factor of 2.5. Thus, if the same sensitivity should be needed, the integration time has to be increased with a multiplier of 2.5.

Is the temperature reading used for compensation purposes, it is recommended to apply the following temporal filtering algorithm. This prevents the compensation of additional noise caused by the temperature reading noise (digitalization, quantization errors and system noise).

x[i]: Current temperature

y[i]: Current temporal filtered temperature y[i-1]: Previous temporal filtered temperature

## 11. Application information

As a help for the user to have an easier understanding of the chip, this chapter lists a variety of typical application examples and their configuration.

#### 11.1. Example sequence from the start-up to frame acquisition

- 1. Apply all positive supplies, while keeping  $\overline{RESET} = 0$ .
- 2. Wait until all positive supplies reach their rated levels.
- 3. Apply the  $V_{BS}$  negative supply, while keeping  $\overline{RESET} = 0$ .
- 4. Wait until V<sub>BS</sub> reached its rated level.
- 5. Optional: Set/check the external 10kOhm pull-up resistors on the strap pins (HSYNC\_A1, VSYNC\_A0).
- 6. Release RESET = 1.
- 7. Wait until the start-up/reset sequence is over (t<sub>Strap\_scan</sub> + t<sub>EEPROM\_to\_CFG\_copy</sub>).
- 8. Optional: Program the TCMI interface signal polarities with respect to the application CPU interface requirements via I<sup>2</sup>C interface.
- 9. Do the counterpart for the parallel data interface settings on the application CPU.
- 10. Optional: Set LED/LED2 driver properties and polarities with respect to external LED/LD circuit on the PCB via I2C.
- 11. Select the measurement mode: TOF or grayscale. Default: 4 DCS TOF mode.
- 12. Set the integration time.
- 13. Start the frame acquisition by using shutter signal (shutter pulse/command).
- 14. Receive transmitted frames from TCMI interface to the external frame buffer on the application CPU.
- 15. Optional: Do a frame acquisition in grayscale mode according to chapter 10. to acquire a grayscale image and read the temperature sensor.
- 16. Loop back to step 12 16.

Note: For corresponding I<sup>2</sup>C communication examples refer to chapter 13.4.7.

## 11.2. 3D TOF distance measurement flow

A 3D TOF distance image will be done with different steps according to Figure 44. Both interfaces of the epc635 are used: The I<sup>2</sup>C for configuration, mode selection and temperature reading (blue marked in the following figures) and the high-speed TCMI for reading the frame data (red marked in the following figures). The sequence starts with the initialization of the epc635 registers with the necessary and correct configuration parameters. Next, the TOF measurement with the expected mode (4 DCS or 2 DCS) will be performed. Depending of the application and the ambient conditions (ambient-light, changing temperature conditions), the TOF measurement needs some compensation. For the purpose of more accurate ambient-light compensation, a grayscale measurement without illumination captures the background light level. Reading of the on-chip temperature sensor (from time to time) helps to compensate thermal influences caused by e.g. the LEDs, the optical filters and the epc635 chip. After the rearrangement of the grayscale image to the correct pixel orientation, the final 3D TOF distance image can be calculated with the necessary compensation.

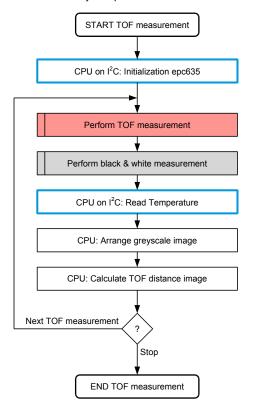


Figure 44: Generic 3D TOF distance measurement flow

The process flow for distance measurements and for grayscale images are similar, see Figure 45. The main difference is the mode selection (number of DCS or grayscale, see register 0x92) and depending thereof the number of frames, which need to be read out during a process cycle. After mode setting, the cycle will be started by applying the SHUTTER signal. Once SHUTTER activated, the epc635 executes the measurement until the end of the sequence automatically.

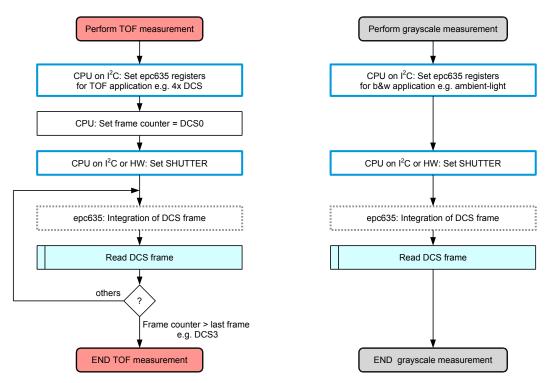


Figure 45: Generic sequences for the distance (TOF) and the grayscale measurement

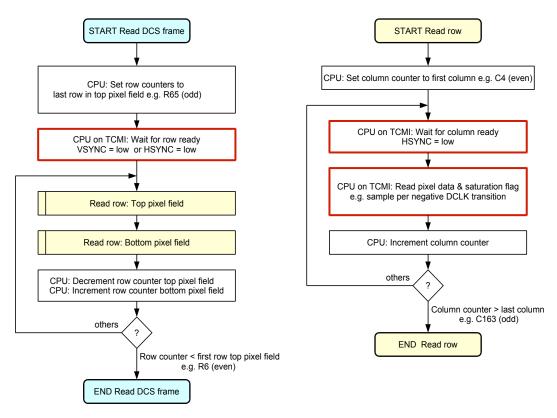


Figure 46: Generic sequences to readout frames and row by row

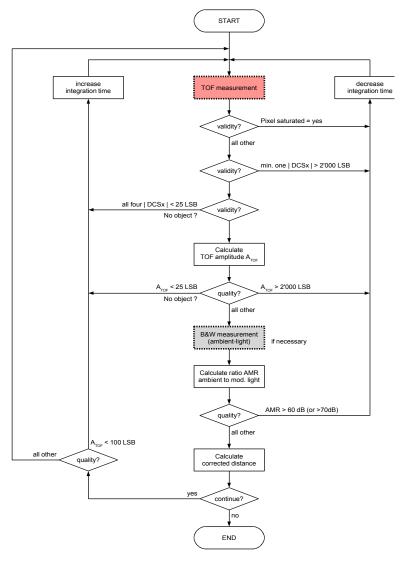


Figure 47: Generic validity and quality flow chart for a single pixel

The generic procedure to readout frames or rows is independent of the selected mode. The application is driven only by the TCMI interface during these phases. To catch the begin of the frame, the application CPU has to wait after the measurement starts until the integration period is finished and the first frame of data is available. The epc635 signals this by setting VSYNC and HSYNC active. Pixel data can be read DCLK by DCLK as long the HSYNC signal is active. Refer also to Figure 28 and Figure 29. The application has to take care to update synchronously all necessary frame, row and pixel readout counters during the measurement cycle.

#### 11.3. Integration time setting

The integration time is the active frame acquisition period (see Figure 28). Specially for moving objects or cameras, this time should be as short as possible to reduce or eliminate motion blur effects. The integration time together with the illumination intensity also defines the effective achievable operating distance. Using the on-chip modulation clock, the integration time can be calculated as

$$[9] \qquad t_{\text{INT}} \, = \, \frac{\text{reg}(0x85) + 1}{80 \text{MHz}} \cdot [\text{reg}(0x\text{A2:}0x\text{A3}) + 1] \cdot \text{reg}(0x\text{A0:}0x\text{A1})$$

Table 27 lists some useful integration time settings.

Integration time	Registers (	0xA0:0xA1)	Registers (0xA2:0xA3)		
	[DEC]	[HEX]	[DEC]	[HEX]	
1.60 µs	1d	0x0001	63d	0x003F	
12.8 µs	1d	0x0001	511d	0x01FF	
102.4 µs	1d	0x0001	4'095d	0x0FFF	
819.20 µs	1d	0x0001	32'767d	0x7FFF	
1.6384 ms	1d	0x0001	65'535d	0xFFFF	

Table 27: Typical TOF and grayscale integration times for 10MHz on-chip modulation frequency (modulation clock = 40MHz)

## 11.4. Special mode setting

In this chapter, the user will find the register setting tables for using special modes. Detailed descriptions are given in the corresponding chapters of these modes; see chapter 8., Pixel-field and operation modes.

### 11.4.1. Dual phase mode (motion blur reduction)

- This mode needs the following basic setting of the register 0x94 = 0x80, register 0x22 = 0x34 and register 0x25 = 0x3E.
- Reset the registers to the default values after leaving this mode: register 0x94 = 0x00, register 0x22 = 0x30 and register 0x25 = 0x35.

Function	Register 0x92	Comments
4x DCS	not applicable	
2x DCS	0x14	Output is effectively 4x DCS in 2 DCS-frames.
Grayscale	not applicable	

Table 28: Setting basic dual phase mode

## 11.4.2. TOF and grayscale single DCS acquisition with 2 different integration times (High dynamic range)

- This mode needs the following basic setting of the register 0x94 = 0x80.
- Reset the register to the default value after leaving this mode: register 0x94 = 0x00.

Mode	Register se	tting	Comments
Function	Register 0x92	Register 0x3C	
4x DCS	0x3C	0x26	
2x DCS	0x1C	0x26	
Ambient only	0xCC	0x26	Grayscale imaging, no active illumination
Ambient & non modulated LED/LD	0xCC	0x16	Grayscale with DC illumination
Ambient & modulated LED/LD	0xCC	0x06	Grayscale with modulated illumination

Table 29: Measurement mode setting for high dynamic range TOF and grayscale

## 11.5. Power consumption

The epc635 has several power states/levels during the different operation phases which are shown in Table 30 and Figure 48.

Power state	Power [mW]	Operation description
RESET	40	All supplies are ON, RESET = 0, Oscillator is ON, PLL and all system system clocks are OFF
READY	110	RESET = 1, PLL and all system clocks ON, waiting for SHUTTER
INTEGRATION	270	SHUTTER pulse/command
CONVERSION	350	Integration finished, conversion of rows
CONVERSION + DATAOUT	320	Transmit row data via TCMI while converting next row
DATAOUT	250	Transmit last row data via TCMI

Table 30: Typical average power consumption levels at different operating states (integration time < 5ms)

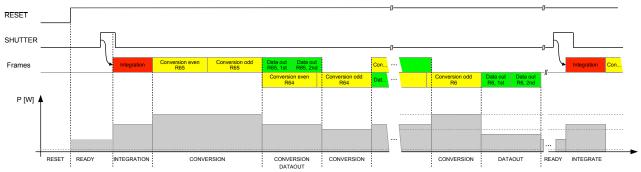


Figure 48: Power consumption levels and operating states

For power critical applications e.g. battery powered systems, it is possible to enforce the epc635 to go in so-called power saving states.

No.	Register			Description
	Name	Address	Value	
Powe	r down			
2	Power control	0xA5	0x00	Switch off of unnecessary supplies
3	Clock control	0x80	0x00	Switch off of unnecessary clocks
4	Mode control	0x7D	0x14	Switch system clock to XTAL clock
5	Mode control	0x7D	0x10	Switch off PLL
Powe	r up			
7	Mode control	0x7D	0x14	Switch on PLL
8	Wait > 32µs			Wait until PLL stable
9	Mode control	0x7D	0x04	Switch system clock to PLL
10	Clock control	0x80	0x3F	Switch on the clocks again
11	Power control	0xA5	0x07	Switch on the supplies again
12	Wait until supplies are stable			
13	Regular 3D TOF operation			

Table 31: Sequence for the SW POWER DOWN mode

## 11.6. Rolling DCS frames

In special applications, it is possible to use all the time the same integration time in continuous distance measurement mode without any grayscale images for ambient-light compensation. Such a set-up allows enhancing the distance measurement rate by a factor of 4 by using rolling DCS frames.

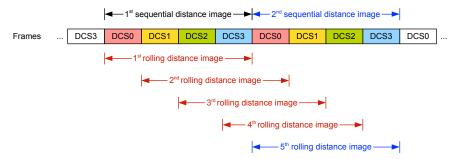


Figure 49: Rolling DCS frames

As shown in Figure 49, the algorithm performs with each new DCS frame a new distance calculation based on the new and last three DCS frames.

## 11.7. Enhanced rolling DCS frame mode

epc635 allows to set for each single DCS access own parameters. This opens the possibility to acquire in time-sequence DCSx frames with e.g. different integration times.

The enhanced rolling mode combines all:

The stacking of integration times to enlarge the dynamic range, the acquisition of an ambient-light image for correction and the rolling mode to speed up the frame rate.

The final distance frame acquisition will be in an equidistant time manner e.g. for 2 or more different integration times.

Select out of the acquired integration time distance frames, already compensated, each time the most reliable distance information for the final composed distance picture

The following example shown here is using two integration times:

50µs for detecting short range objects and 2ms doing the same for the long range.

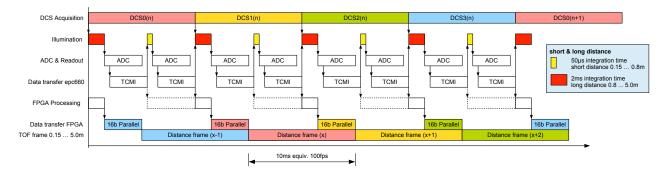


Figure 50: Enhanced rolling mode sequence with 2 integration times

Implementation example step by step: Rolling mode using 3 integration times

- 1. Chose single frame mode by setting register 0x22 and 0x92.
- 2. Run 4 DCS turns by
- Select DCS0 and acquire 3 DCS0 each with one of the 3 integration times
   Integration time t1 > shutter > readout > integration time t2 > shutter > readout > integration time t3 > shutter > readout.

   2<sup>nd</sup> and following turns:

Calculate for each integration time the distance and TOF amplitude image with the last 4 corresponding DCS frames. Select out of the acquired integration time distance images, already compensated, each time the most reliable distance information and compose the actual final distance picture.

- 4. Select DCS1 and acquire 3 DCS1each with one of the 3 integration times Integration time t1 > shutter > readout > integration time t2 > shutter > readout > integration time t3 > shutter > readout 2<sup>nd</sup> and following turns:
  - Calculate for each integration time the distance and TOF amplitude image with the last 4 corresponding DCS frames. Select out of the acquired integration time distance images, already compensated, each time the most reliable distance information and compose the actual final distance picture.
- ... and so on ...

	Register	0x22	0x25	0x92
Mode	DCS/Shutter	DCS select 1 <sup>st</sup> frame	DCS select 2 <sup>nd</sup> frame	Modulation select
4 DCS	DCS 0, 1, 2, 3	0x34	0x3D	0x30
2 DCS	DCS 0, 1	0x34	0x3D	0x10
	DCS 2, 3	0x32	0x33	0.00
1 DCS rolling	DCS 0	0x34		
	DCS 1	0x31	Notuced	0,,00
	DCS 2	0x32	Not used	0x00
	DCS 3	0x33		

Table 32: DCS selection for enhanced rolling mode

## 12. Parameter and configuration memory

## 12.1. Sequencer program

The sequencer program is the executable code of the chip's state-machine. ESPROS' intention is running always best chip performance by offering the user best suited sequencer program code in the download package of the evaluation kit. After each power-up, this program code must be downloaded by the application to the chip via the I<sup>2</sup>C interface. Refer to chapter 15.10.

#### IMPORTANT NOTICE

Use always latest sequencer program which lists in its file header the corresponding chip type and version. Wrong sequencer programs will derate chip performance or even worse, lead to malfunction.

#### 12.2. Data memory map

The epc635 control registers (RAM) are used for controlling all features of the chip. They are organized as 256x8 bit into 0x00 ... 0xFF address locations. The address space 0x80 ... 0xFF is EEPROM backed-up. EEPROM parameters in this section are stored permanently between the power off/on cycles. All registers can be accessed through I<sup>2</sup>C interface by the application CPU (see chapter 13. I2C interface). Multiple byte registers are stored in the order MSB first, then LSB.

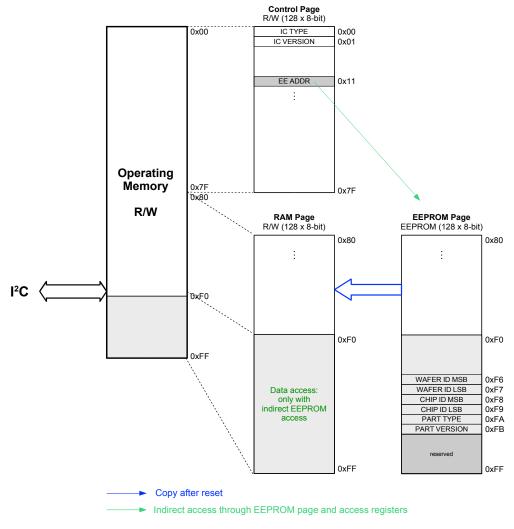


Figure 51: Memory map

## 12.2.1. Control page

The control page contains R/W accessible registers with default values during startup. The content can be changed via the  $l^2C$  interface. The changed values are preserved as long as the IC is powered. They are set back to their default values with a reset.

#### 12.2.2. RAM page

The RAM page contains R/W accessible registers with EEPROM copied values after startup. The content can be changed via the I<sup>2</sup>C interface. The changed values are preserved as long as the IC is powered. They are set back to EEPROM values with a reset.

## 12.2.3. EEPROM page

The embedded 128x8-bit EEPROM stores operation parameters as well as factory set trimming and calibration values.

## 13. I<sup>2</sup>C interface

The I<sup>2</sup>C-bus interface allows accessing the R/W registers and the programming of the EEPROM registers which store the configuration parameters. It is the only interface through which the configuration registers can be accessed (Figure 51 and Table 35) by the application. It works as a slave device according to the I<sup>2</sup>C specification (refer to chapter 16.2.) with a transfer rate of up to 400 kbit/s in Fast Mode (FM) or 1Mbit/s in Fast Mode plus (FM+). The I<sup>2</sup>C master such as an external CPU can set the transfer speed simply by driving the SCL input at that frequency (up to 1MHz), therefore there is no prior register configuration or setting necessary.

I<sup>2</sup>C specification is supported in epc635 with following remarks/exceptions:

- 7-bit addressing only is supported
- Clock stretching is supported
- General call address: By transmitting 0x00 followed by 0x06 (issues software reset) or transmitting 0x00 followed by 0x04 (device address reload), the programmable part (A0, A1) of the I<sup>2</sup>C address pins is overwritten by the initially scanned value through strap pins during start-up or reset phase
- Software reset is supported
- Other uses of I2C bus are not supported.

#### 13.1. Device addressing

The epc635 7-bit I<sup>2</sup>C device address is hard-wired to the value shown below in Figure 52. Two address bits A0, A1 can be optionally initialized as 1 through strap pins (chapter 5.6.3.). In a typical single-camera 3D TOF imager application in which epc635 is directly connected as a single I<sup>2</sup>C slave to a single I<sup>2</sup>C master, the strap pins can be used without any external pull-up resistors. In this case, the device address is set after reset default as 0100000. In a multi-camera application with up to 4 epc635 devices connected on the same I<sup>2</sup>C bus as slaves or together with other I<sup>2</sup>C slaves talking to a single I<sup>2</sup>C master, external pull-up resistors can be utilized on the strap pins to initialize different I<sup>2</sup>C device addresses in order to correctly identify different epc635 slaves on the bus.

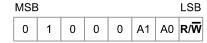


Figure 52: Device address through I2C

#### 13.2. I2C bus protocol notation

The following notation is used:

- S START condition
- P STOP condition
- A Acknowledge last byte (ACK)
- A Not-Acknowledge last byte (NACK)
- Shaded part of protocol: transmitted by master
- Unshaded part of protocol: transmitted by epc635

## 13.3. I2C bus timing

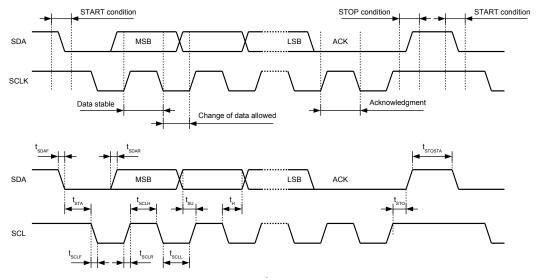


Figure 53: I2C bus timing

Symbol	Parameter	Min.	Max.	Units
t <sub>SCLL</sub>	SCL clock low time	0.5		μs
t <sub>SCLH</sub>	SCL clock high time	0.26		μs
t <sub>su</sub>	SDA setup time	50		ns
t <sub>H</sub>	SDA hold time		0	ns
t <sub>SDAR</sub> / t <sub>SCLR</sub>	SDA and SCL rise time		120	ns
t <sub>SDAF</sub> / t <sub>SCLF</sub>	SDA and SCL fall time		120	ns
t <sub>STA</sub>	Start condition hold time	0.26		μs
t <sub>STO</sub>	Stop condition setup time	0.26		μs
t <sub>STOSTA</sub>	Stop to start condition time (bus free)	0.5		μs
Сь	Capacitive load for each bus line		550	pF
t <sub>SP</sub>	Pulse width of the spikes which are filtered		50	ns

Table 33: I<sup>2</sup>C bus timing: Timing parameters (FM+)

#### 13.4. I<sup>2</sup>C commands

## 13.4.1. Software reset

(0x00, 0x06) issues a software reset, same behavior like hardware reset.

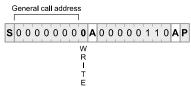


Figure 54: Software reset through I2C

#### 13.4.2. Device address reload

(0x00, 0x04) activates the I<sup>2</sup>C address stored in register 0xCA. Note that the values of A0 and A1 cannot be changed by software. Therefore, this general call command only works for bits 2 to 6 of register 0xCA (chapter 5.6.3).

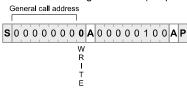


Figure 55: Device address A1, A0 reload through I2C

## 13.4.3. Write single-byte

During a single-byte write, only one register is written. After the device address is transmitted, the master has to transmit the register address and the write data in two I<sup>2</sup>C data packets (Figure 56). The access is terminated by a STOP condition.



Figure 56: Single-byte Write access through I2C

## 13.4.4. Write multi-byte

During a multi-byte write operation, the master transmits the device address and the address of the first register to be written. All subsequent bytes until the STOP condition are interpreted as write data packets (Figure 57). The write address pointer is incremented internally. Do not transmit more bytes that the write address pointer reaches the limit of the address space (see chapter 14., Table 35, Table 36).

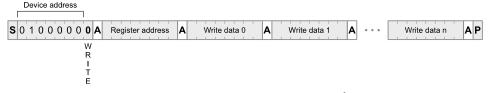


Figure 57: Multi-byte Write access through I2C

#### 13.4.5. Read single-byte

The master transmits first the device address with a write command. Next, it writes the register address to be read. Then, the master transmits the device address again with a read command where the epc635 answers with the data stored in the addressed register. Finally, the master terminates the read sequence with a NACK and a STOP (Figure 58).

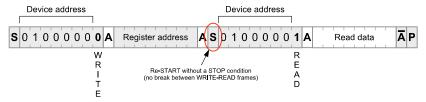


Figure 58: Single-byte Read access through I2C

#### 13.4.6. Read multi-byte

The master transmits first the device address and the address of the first register to be read. After the epc635 is addressed with a read command, epc635 answers with read data bytes until the master does not acknowledge a byte. The master is expected to terminate the access with a STOP condition thereafter (Figure 59). During the access the read address pointer is incremented epc635 internally. Do not transmit more bytes that the write address pointer reaches the limit of the address space (see chapter 14., Table 35, Table 36).

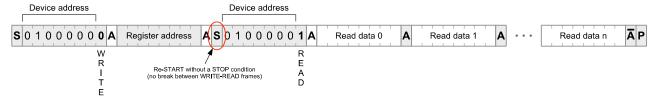


Figure 59: Multi-byte Read access through I2C

#### 13.4.7. Command timing

The operating modes of the epc635 are initialized, activated, deactivated and monitored by sending several single or multi-byte write and read command sequences through I<sup>2</sup>C interface. This section lists and explains available commands together with their access time ( $f_{SCL} = 1MHz \rightarrow t_{SCL} = 1\mu s$ ).

There is no particular order defined for sending the commands. The only requirement is having no on-going frame acquisition process when updating non-shadowed registers. The registers marked with \*\* in the register map can be updated on-the-fly during a frame acquisition. New values are used by the next frame.

Command	Description	Length [Bytes]	Time [µs]
Single-byte Write	Single-byte write to control registers	3	29
Multiple-byte Write	Multiple-byte write (n bytes) to control registers	2 + n	20 + n x 9
Single-byte Read	Single-byte read from control registers	4	39
Multiple-byte Read	Multiple-byte read (n bytes) from control registers	3 + n	30 + n x 9
Mode set	4, 2, or 1 DCS mode set using register 0x92	3	29
Integration time (short) set	Integration time set (up to 800µs) using integration length 1 registers	4	38
Integration time (long) set	Integration time set using integration time multiplier and length 1 registers	6	56
Dual Integration time (long) set	Dual int. time set using integration time multiplier and length 1, 2 registers	8	74
Shutter	Start frame acquisition by using the shutter control register	3	29
Integration time (short) + Shutter	Integration time + soft shutter in one go! (Integration length 1 registers, shutter control register)	5	47
EEPROM Indirect Single Write	Indirect single write to EEPROM	9	20ms
EEPROM Indirect Single Read	Indirect single read from EEPROM	10	97

Table 34: I<sup>2</sup>C Control commands summary

# 14. Register map

## Notes:

\*\* Shadow registers can be updated on-the-fly while a frame acquisition is going on. The new values are used at the start of the next frame.

Not listed registers are reserved and must not be altered by the user. Otherwise, chip malfunction can occur. However, if a register is accidentally overwritten, a RESET restores the factory settings.

The listed default values are after downloading the latest sequencer program to the chip.

## 14.1. Control page 0x00 ~ 0x7F

Addr.	Туре	Default	Descri	ntion		
0x00	R			for device family identification. For chip type refer to register 0xFA.		
0x01	R			ion for device mask identification. For chip version refer to register 0xFB.		
0x11	R/W			s register for indirect read/write access to EEPROM (refer to 15.5. and 15.6.)		
0x12	R/W			egister for indirect read/write access to EEPROM (refer to 15.5. and 15.6.)		
0x1C	R/W	0x1E		ESM FS: frame start label (refer to 6.5)		
0x1D	R/W	0xE1		ESM FE: frame end label (refer to 6.5)		
0x1E	R/W	0xAA		ESM LS: line start label (refer to 6.5)		
0x1F	R/W	0x55	+	ESM LE: line end label (refer to 6.5)		
0x20	R	0x00		can register high (refer to 5.6.3):		
OXLO	'`	OXOG	Bit		Default	
			04	reserved	0	
			5	Strap input 0: I <sup>2</sup> C address A0	0	
		6	Strap input 1: I <sup>2</sup> C address A1	0		
			7	reserved	0	
				start-up values of these registers are only valid until end of reset phase. Values	might be over-	
				by external pull-up resistors during strap scan phase when reset is released.		
0x22	R/W	0x30	DCS se	election for 1st frame (refer to the chapter 11.7):		
		Bit	Function	Default		
			0	mgx0 modulator (mga0, mgb0)	0	
			1	00: DCS 0	0	
			'	01: DCS 1		
					10: DCS 2   11: DCS 3	
			2		0	
				mgx1 modulator (mga1, mgb1) 00: DCS 0		
			3	01: DCS 1	0	
				10: DCS 2		
				11: DCS 3		
			47	reserved	0x3	
0x25	R/W	0x35		election for 2 <sup>nd</sup> frame (refer to the chapter 11.7):		
			Bit	Function	Default	
			0	mgx0 modulator (mga0, mgb0)	1	
			1	00: DCS 0	0	
				01: DCS 1 10: DCS 2		
				11: DCS 3		
			2	mgx1 modulator (mga1, mgb1)	1	
				00: DCS 0		
			3	01: DCS 1	0	
				10: DCS 2   11: DCS 3		
					0x3	
			47	reserved		

Table 35: Address map of the control page  $(0x00 \sim 0x7F)$ 

Addr.	Type	Default	Descri	ption				
0x3A	R/W	0x00	0x10: s	Readout mode for grayscale 0x10: single-ended readout (negative numbers are clipped) 0x00: differential readout. Select this mode by the user application, refer to chapter 9.3 and 10.1				
0x3C	R/W	0x26	Modula	tion control in grayscale mode:				
			Bit	Function	Default			
			0	reserved	0			
			12	reserved	1			
			3	reserved	0			
			4	0: LED/LD modulated 1: LED/LD on during integration	0			
			5	0: LED/LD modulated 1: LED/LD off during integration	1			
			67	reserved	0			
0x60	R							
0x61	R		Tempe	rature sensor, refer to chapter 10				
0x71	R/W	0x00		r of fine DLL delay steps to delay the LED output by approx. 10ps per step. Valid onl				
0x72	R/W	0x00		r 0xAE is enabled. Refer also to register 0xAE and chapter 5.8. Max. value is 799 (0x Delay is sensitive to VDD variations and noise.	(31F).			
0x73	R/W	0x00	registe	r of coarse DLL delay steps to delay the LED output by approx. 2ns per step. Valid of 0xAE is enabled. Refer also to register 0xAE and chapter 5.8. Max. value is 49 (0x30) delay is sensitive to VDD variations and noise.				
0x7D	R/W	0x04	Mode o	control:				
			Bit	Function	Default			
			01	reserved	0			
			2	Enable PLL 0: disable 1: enable	1			
			37	reserved	0			

Cont. Table 35: Address map of the control page  $(0x00 \sim 0x7F)$ 

## 14.2. RAM page (0x80 ~ 0xEF)

Addr.	Type	Default	Descri	ption						
0x80	R/W	0x3F	Clock	Clock control:						
			Bit	Function	Default					
			05	reserved	1					
			6	Modulation clock source 0: Internal modulation clock 1: External clock from MODCLK input	0					
			7	reserved	0					
0x85	R/W	0x01	Modula	ation clock divider:						
			Bit	Function	Default					
			0	Modulation clock divider provides clock to the LED/Pixel-field modulator/demodulator circuits by integer division of the internal PLL clock or external MODCLK:	1					
			1		0					
			2	f <sub>mod_cik</sub> = 80MHz / (modulation clock divider + 1)	0					
			3 4	Default: $80MHz / (0x01 + 0x01)$ : $f_{mod\_clk} = 40MHz$ Maximal value of modulation clock divider = $0x1F$ : $f_{mod\_clk} = 2.5MHz$ Note: The LED modulation frequency is 4 times lower than $f_{mod\_clk}$						
			57	reserved	0					
0x89	R/W	0x03	TCML	clock control:						
0x09	0x89 R/W	0x03	Bit	Function	Default					
									0	
			1	TCMI clock divider:	1					
			2	f <sub>tcmi_clk</sub> = 80MHz / (TCMI clock divider + 1)	0					
			3	Default: 80MHz / (0x03 + 0x01) = 20MHz Maximal value of TCMI clock divider = 0x1F = 2.5MHz	0					
			4		0					
			56	reserved	0					
			7	DCLK skew enable: 0: disable 1: enable Used to delay DCLK edge (typ. 2ns) to compensate PCB delays. Might be particularly useful when TCMI clock divider = 0 (divided by 1). When set normal, DCLK edge is centred with respect to other TCMI *SYNC*, DATA[7:0] outputs.	0					
0x8B	R/W	0x01	used to 12.5ns modula 0: no 1: 1 ( 2: 2 (	er of PLL clock periods delay of the demodulation signal path (all modulation modes). In insert a phase shift between modulation (LED) and demodulation (pixel). 1 PLL clock (a) 80MHz PLL clock. This is equivalent to a distance shift of 1.875m independent of a distance. Note: This phase shift is temperature independent. In delay clock clock (clock)	k cycle is					

Table 36: Address map of the RAM page ( $0x80 \sim 0xEF$ )

Addr.	Type	Default	Descri	ption	
0x90	R/W	0xC4		iver control:	
			Bit	Function	Default
			0	reserved	0
			1	Inverts output signals LED and LED2 if drivers are enabled 0: not inverted, e.g. LED = 0, not active: Pin LED non-conductive, LED2 = VSSIO. 1: inverted, e.g. LED = 0, not active: Pin LED conductive, LED2 = VDDIO.	0
			2	LED output select:  0: LED driver is disable. Pin LED is non-conductive.  1: LED driver is enabled.	1
			3	reserved	0
			4	LED/LD permanently on (torch function, no modulation) if drivers are enabled: 0: off 1: on (Refer to IMPORTANT NOTE chapter 5.7)	0
			5	LED2 output select: 0: LED2 driver disabled. Output is in Tri-State with termination resistor to VSSIO. 1: LED2 driver enabled.	0
			67	reserved	1
0x91	R/W	0x03	Segue	ncer control:	
0.51	10,00	0.00	Bit	Function	Default
			01	reserved	1
			35	reserved	0
			6	If enabled, avoids readout rollover when using slower DCLKs e.g. DCLK < 10MHz.	0
				Stretches HSYNC for slower TCMI interface. Causes reduced DCS frame rate due to additional 2μs per ADC conversion (tconv/2 + 2μs).  0: disable for DCLK > 10MHz (default)  1: enable for DCLK = 10MHz or lower	J
			7	reserved	0
0.0044	5.44				
0x92**	R/W	0x34	Bit	tion select: Function	Default
			01	reserved	0
			2	reserved	1
			3	Dual integration time mode – acquisition with 2 integration times per DCS frame using additionally integration length 2 registers 0x9E and 0x9F:  0: disable 1: enable Needs register 0x94 set to 0x80, otherwise it is not effective (see Figure 38)	0
			4	Number of DCS readouts select:	1
			5	00: Grayscale mode, DCS0 only 01: Dual phase mode, DCS0, DCS1 or DCS2,DCS3 10: reserved 11: Full resolution mode or dual int. mode, DCS0, DCS1, DCS2, DCS3	1
			6	Modulation select:	0
			7	00: TOF mode 01: reserved 10: reserved 11: Grayscale mode	0
0x94**	R/W	0x00	0x00: [	perating and readout control. Refer to chapter 8.2 and 11.4: Default, TOF mode: full resolution mode Dual phase or dual integration time mode	

Cont. Table 36: Address map of the RAM page (0x80  $\sim$  0xEF)

Addr.	Type	Default	Description			
0x9D**	R/W	0x50	ADC resolution control, refer to chapter 8.4: 0x50: 12 bit resolution 0x34: 8 bit resolution			
0x9E**	R/W	0x07	Integration length 2: Number of modulation clock periods for the second integration time in the dual inte-			
0x9F**	R/W	0xFF	gration time mode (refer to 8.2.3, default: 2'047). See registers 0xA2 and 0xA3 for functional definition details.  Bit 3 in register 0x92 has to be set to 1 to enable this integration time for the even rows. The odd rows operate with the integration length 1 set in registers 0xA2 and 0xA3.			
0xA0**	R/W	0x00		Integration time multiplier (10 bit value) for integration lengths set with the integration length registers		
0xA1**	R/W	0x01	(defau	(default = 1, min. value = 1). This multiplier is active on both settings integration length 1 and 2.		
0xA2**	R/W	0x07	Integration length 1: Number of modulation clock periods for the (first in the dual integration time mode			
0xA3**	R/W	0xFF	Integra e.g. for Note: (	integration time (16 bit value, default = 2'047, min. value = 7 which is integration time 200ns @ 10MHz). Integration time = Integration time multiplier * (Integration length +1) * t <sub>mod_clk</sub> e.g. for defaults @ 10MHz modulation clock = 51.2µs Note: (Integration length + 1) should be evenly divisible by 4.		
0xA4	R/W	0x00	Shutte	r Control:		
			Bit	Function	Default	
			0	Shutter release. Refer to chapter 6.2 0: disable 1: enable. In single shot mode: Starts acquisition and is auto cleared. Note: Shutter release is not auto-cleared when multiple frames is enable.	0	
			1	Multiple frames (auto-run or video mode). Refer to chapter 6.2 0: disable. Single shot mode. 1: enable. Multiple frame mode active if shutter enabled. Refer to chapter 6.2.2.	0	
			27	reserved	0	
0xA5	R/W	0x07 0x01	Power control (Refer also to 11.5.) 0x00: Power off 0x07: Power on DLL control (Refer also to register 0x73 and chapter 5.8):			
074 t=		5/10 1	0x01: no delay 0x04: delay manually set by register 0x73			
0xCA	R	0x20	Bit	Function	Default	
			1	reserved, I <sup>2</sup> C address A1, A0 of 7-bit I <sup>2</sup> C device address. Programmable only during reset via strap pins using external pull-up resistors.	0	
			2		0	
			3		0	
			4	l <sup>2</sup> C device address A6 A2 of 7-bit l <sup>2</sup> C device address.  Programmable via direct access from l <sup>2</sup> C or from EEPROM during start up, fol-	0	
			5	lowed by an I <sup>2</sup> C general call "Device address reload" to take it into effect.	1	
			6		0	
			7	reserved	0	
			ļ	1		

Cont. Table 36: Address map of the RAM page (0x80 ~ 0xEF)

Addr.	Type	Default	•		
0xCB	R/W	0x23	I <sup>2</sup> C and TCMI control:		
			Bit	Function	Default
			0	I <sup>2</sup> C clock stretching 0: disabled 1: enabled	1
			1	l²C pins input spike filter 0: disabled (> 1MHz) 1: enabled (≤ 1MHz, FM+) When l²C pins input spike filter = 0, SDA and SCL pins can be used up to 10MHz as inputs (driven rail-to-rail by a real CMOS driver, no pull-up) and up to 2MHz as outputs.	1
			2	TCMI ESM mode enable (refer to 6.5) 0: disabled 1: enabled	0
			3	TCMI DCLK mode select (refer also to 6.1.) 0: continuous 1: gated	0
			4	TCMI data format (refer also to 6.4).	0
			5	01: 8 bit mode. Transfers the 8 MSB bits of the pixel data with 1x DCLK. 10: Isb/msb split mode: Transfers 12 bit pixel data with LSByte leading and MS-Byte trailing with 2x DCLK. Data are MSB aligned (default). The optional SAT bit is on the LSB. 11: msb/lsb split mode: Transfers 12 bit pixel data with MSByte leading and LS-Byte trailing with 2x DCLK. Data are MSB aligned. The optional SAT bit is on the LSB.	1
			6	When split modes selected (= 11 or 10), forces bit DATA[0] of the LSByte = 1 when the pixel is saturated. Not effective with other TCMI data formats.  0: disabled 1: enabled	0
			7	reserved	0
0,,00	D/M	N 0::00	TOM:	aladh a attions	
0xCC	R/W	R/W 0x00	Bit	polarity settings: Function	Default
			0	DCLK edge select to align all other TCMI outputs 0: falling edge 1: rising edge	0
			1	HSYNC polarity 0: HSYNC active low 1: HSYNC active high	0
			2	VSYNC polarity 0: VSYNC active low 1: VSYNC active high	0
			3	XSYNC polarity 0: XSYNC active low 1: XSYNC active high Only effective when bit 6 is set to 0	0
			4	DATA[11:0] unsigned/signed TCMI data output format 0: unsigned integer, subtract 2'048 to get correct value (Default) 1: two's complement signed integer (-2'048 2'047).	0
			5	reserved	0
			6	Select XSYNC / SAT output pin function 0: XSYNC 1: SAT	0
			7	Force DATA[11:0] = 0xFFF (unsigned) / 0x7FF (signed, two's complement) during data-out operation when corresponding pixel is saturated 0: disabled 1: enabled	0

Cont. Table 36: Address map of the RAM page (0x80 ~ 0xEF)

Addr.	Type	Default	Description	
0xCD	R/W	0x13	ADC control, refer to chapter 8.4: 0x13: 12 bit resolution 0x1B: 8 bit resolution	
			Registers 0x9D must be set according chapter 8.4	
0xE8	R/W		Temperature offset correction for the calculation according the formula in chapter 10 by the application SW. Range approx27 +27°C with around 0.2°C steps. The reference temperature is +27°C. 0x7F (127) corresponds to 0°C offset. 0xFF: Function is not supported.	
0xE9	R/W		DLL step. Supported for Wafer IDs 40 or higher. Refer for details to register 0x73 and Figure 20. The exact value is $t_{DLL}$ = ((register 0xE9 -128) * 0.003ns) + 2.1ns (at +27°C, $V_{DD}$ , $V_{DDPLL}$ = 1.8V). 0xFF: Function is not supported.	

Cont. Table 36: Address map of the RAM page (0x80 ~ 0xEF)

## 14.3. EEPROM page, indirect data access section (0xF0 ~ 0xFF)

Addr.	Type	Default	Description
0xF0	R/W	0x00	User register for user data. Do not write the register during frame acquisition. The number of WRITE cycles into the EEPROM should not exceed 100 WRITE operations.
0xF5	R	0x00	Customer ID
0xF6	R		Wafer ID
0xF7	R		
0xF8	R		Chip ID
0xF9	R		
0xFA	R	0x04	Chip and part type: 0x04 = epc635
0xFB	R		Chip and part version (release) e.g. 0x01 for version -001

Table 37: Address map of the EEPROM page (0xF0 ~ 0xFF)

## 15. Control command examples

To simplify command sequence definitions, following C-programming language style functions are defined for the I<sup>2</sup>C master CPU:

- i2cGeneralCall(byte genAdr, byte cmd); //  $20 \times t_{SCL} = 20 \mu s$ ■ i2cSingleWrite(byte devAdr, byte regAdr, byte regVal); //  $29 \times t_{SCL} = 29 \mu s$
- i2cMultiWrite(byte devAdr, byte regAdr, byte\* regVal, byte n // 20 + (n x 9 x t<sub>SCL</sub>) = 20 + (n x 9)µs
- byte i2cSingleRead(byte devAdr, byte regAdr); //  $39 \times t_{SCL} = 39 \mu s$
- byte\* i2cMultiRead(byte devAdr, byte regAdr, byte n); // 30 + (n x 9 x t<sub>SCL</sub>) = 30+(n x 9)µs

#### 15.1. Software reset

PRECONDITION: None

```
    i2cGeneralCall(0x00, 0x06);
    Software reset, same effect like RESET pin, 20μs
    ...
    Wait for t<sub>RESET</sub> (> 100ns)
```

## 15.2. 4 DCS: Acquire DCS0 ... 3 frames with $t_{int}$ = 20 $\mu$ s @ 10MHz modulation frequency

PRECONDITION: All other registers contain default values.

```
    i2cSingleWrite(0x20, 0x92, 0x34);
    i2cSingleWrite(0x20, 0x92, 0x34);
    i2cMultiWrite(0x20, 0xA2, &(0x031F), 2);
    i2cSingleWrite(0x20, 0xA4, 0x01);
    i2cS
```

## 15.3. 4 DCS: Acquire DCS0 ... 3 frames with $t_{int}$ = 20µs, followed by DCS 0 ... 3 with $t_{int}$ 400µs @ 10MHz mod. frequency

PRECONDITION: All other registers contain default values.

```
    i2cSingleWrite(0x20, 0x92, 0x34);
    i2cMultiWrite(0x20, 0xA2, &(0x031F), 2);
    i2cSingleWrite(0x20, 0xA2, &(0x031F), 2);
    i2cSingleWrite(0x20, 0xA4, 0x01);
    i2cSingleWrite(0x20, 0xA4, 0x01);
    i2cMultiWrite(0x20, 0xA4, 0x01);
    i2cMultiWrite(0x20, 0xA2, &(0x3E7F), 2);
    i2cSingleWrite(0x20, 0xA2, &(0x3E7F), 2);
    i2cSingleWrite(0x20, 0xA4, 0x01);
    i2cSingleWrite(0x20, 0xA4, 0x
```

## 15.4. 2 DCS: Acquire DCS0 and 1 frames with t = 20µs @ 10MHz modulation frequency

PRECONDITION: All other registers contain default values.

```
    i2cSingleWrite(0x20, 0x92, 0x14); // Modulation control 0x92 = 0x34 (mod. sel. = 00, No. DCS = 11), 29μs
    i2cMultiWrite(0x20, 0xA2, &(0x031F), 2); // Integration length 1 0xA2/0xA3 = 0x031F (integration time = 20μs), 38μs
    i2cSingleWrite(0x20, 0xA4, 0x01); // Shutter control 0xA4 = 0x01, (shutter release = 1), 29μs
    ... // Acquisition starts. Wait until all 2x DCS frames are finished.
```

## 15.5. Indirect single write to EEPROM: Store 1 byte at user register 0xF0

PRECONDITION: None

```
    i2cSingleWrite(0x20, 0x11, 0xF0); // EEPROM address register 0x11 = 0xF0, 29μs
    i2cSingleWrite(0x20, 0x12, 0x22); // EEPROM data register 0x12 = 0x22 // (user register 1 = 0x22), 29μs + 20ms = ~20ms
```

3. ...

- Note 1: Start address is written in address register 0x11 for indirect read/write access to the EEPROM.
- Note 2: Each EEPROM data register write starts erase/programming EEPROM. Each EEPROM write takes 20ms.
- Note 3: Corresponding control register value is not modified. Only EEPROM register is modified.
- Note 4: EEPROM content will only be copied to corresponding control register after RESET.

### 15.6. Indirect single read from EEPROM: Read 1 byte from user register 0xF0

PRECONDITION: None

```
    i2cSingleWrite(0x20, 0x11, 0xF0); // EEPROM address register 0x11 = 0xF0, 29μs
    cal1 = i2cSingleRead(0x20, 0x12); // user value 1 = EEEPROM data register (user register 1 0xF0), 39μs
    ...
```

Note 1: Start address is written in the EEPROM address register 0x11.

Note 2: Corresponding control register value is not modified. Only EEPROM is read.

#### 15.7. Reading part version (register 0xFB)

Since there is no RAM register at address 0xFB, the PART VERSION can only be read directly from the EEPROM.

```
# The syntax of the I2C commands is as follows:
# Reading: i2c r REGISTER_ADDRESS [NUMBER_OF_BYTES]
# Writing: i2c w REGISTER_ADDRESS [DATA1 DATA2 ...]

i2c w 11 FB
i2c r 12 01 # Response: PART VERSION
```

## 15.8. Reading IC version (register 0x01)

I2C command to read IC version

```
# The syntax of the I2C commands is as follows:
# Reading: i2c r REGISTER_ADDRESS [NUMBER_OF_BYTES]

i2c r 01 01 # Response: IC VERSION
```

## 15.9. Reading WAFER ID and CHIP ID

It can be necessary for technical support to read the WAFER ID and the CHIP ID. Since there are no RAM register at addresses 0xF6 to 0xF9, the WAFER ID and the CHIP ID can only be read directly from the EEPROM.

```
# The syntax of the I2C commands is as follows:
# Reading: i2c r REGISTER_ADDRESS [NUMBER_OF_BYTES]
# Writing: i2c w REGISTER_ADDRESS [DATA1 DATA2 ...]

i2c w 11 F6
i2c r 12 01 # Response: WAFER ID MSB
i2c r 12 01 # Response: WAFER ID LSB
i2c r 12 01 # Response: CHIP ID MSB
i2c r 12 01 # Response: CHIP ID LSB
```

## 15.10. Latest version of the sequencer program

Use the sequencer program from the latest version of the evaluation kit download package, e.g. epc635\_Seq\_Prog-V10.

- 1. Start up epc635 chip.
- 2. Wait until the chip is in READY state.

- 3. Prior activating the shutter, download the following program by I<sup>2</sup>C for reprogramming the epc635.
- 4. The chip is now ready to be used according to the data sheet.

Download code demonstration example:

```
# epc635_Seq_Prog-V10
# This program is for following epc635 chip versions:
# -001
# The following sequence of I2C commands re-programs an
# epc635 chip in order to be on most actual functionality.
#
# The syntax of the I2C commands is as follows:
# Writing: i2c w REGISTER_ADDRESS [DATA1 DATA2 ...]
i2c w a4 00
i2c w 91 00
i2c w 47 01
i2c w 40 01 43 10 00 00 00 00 0D
i2c w 40 01 43 10 00 00 01 00 0D
i2c w 40 01 43 10 00 00 00 0D
i2c w 40 03 43 10 10 02 58 00 0D
i2c w 40 03 43 10 10 02 58 00 0D
i2c w 40 04 43 10 20 01 80 00 0D
i2c w 40 05 43 10 00 160 00 0D
i2c w 40 06 43 10 00 01 60 00 0D
i2c w 40 06 43 10 00 01 60 00 0D
i2c w 40 07 43 10 00 07 80 00 0D
i2c w 40 07 43 10 00 07 80 00 0D
i2c w 40 07 43 10 00 01 60 00 0D
i2c w 40 9B BC 0A FO 00 0C 54 00 0D
i2c w 40 9D BD 0E CO 06 50 00 0D
i2c w 47 00
i2c w 47 00
i2c w 47 00
i2c w 90 03
i2c w 90 04
i2c w AE 01
```

#### **IMPORTANT NOTES:**

- Default configuration: Register LED\_driver 0x90, bit 3 = 0, 0xAB = 0x00. Refer also to Chapter .1.6.
- Register 0xAE: Set the value to 0x01 (DLL bypassed).

## 16. Addendum

# 16.1. Terms, definitions and abbreviations

Abbreviation	Term, Definition	Explanation
ABS	Automatic Backlight Suppression	
ADC	Analog Digital Converter	
AMR	Ratio of ambient-light / modulated light	
CGU	Clock Generation Unit	
CSP	Chip Scale Package	
DCS	Differential Correlation Sample	
DLL	Delay Locked Loop	Delay line only in the implementation of epc635
fps	Frames per second	
Half-QQVGA	1/8 of a Quarter VGA	160x60 pixel resolution
HDR	High Dynamic Range	
IC	Integrated Circuit	
LED/LD	Light Emitting Diode / Laser Diode	
LSB	Least Significant Bit	
MGA	Modulation Gate A	
MGB	Modulation Gate B	
MGX	Modulation Gate A or B	
mga	MGA control signal	
mgb	MGB control signal	
mgx	MGX control signal	
MSB	Most Significant Bit	
OSC	Oscillator	
PLL	Phase Locked Loop	
QVGA	Quarter VGA	320x240 pixel resolution
SGA	Storage Gate A	
SGB	Storage Gate B	
SGX	Storage Gate A or B	
TCMI	TOF Camera Module Interface	
TOF	Time of Flight	
VGA	Video Graphics Array	640x480 pixel resolution
XTAL	Crystal	

Table 38: Definitions and Abbreviations

## 16.2. Related documents

- 3D-TOF, A guideline to 3D-TOF sensors that work, Beat De Coi, ISBN 978-3-033-07096-7.
- Application note AN08 Process-Rules CSP Assembly, ESPROS Photonics corp.
- Application note AN10 Calibration and compensation of Cameras using ESPROS TOF Chips, ESPROS Photonics corp.
- Application note AN11 DME 660 Photobiological Safety Analysis, ESPROS Photonics Corp.
- Application note AN12 TOF data improvement toolbox, ESPROS Photonics Corp.
- NXP I<sup>2</sup>C-bus specification: I<sup>2</sup>C Bus Specification and User Manual, NXP corp.

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